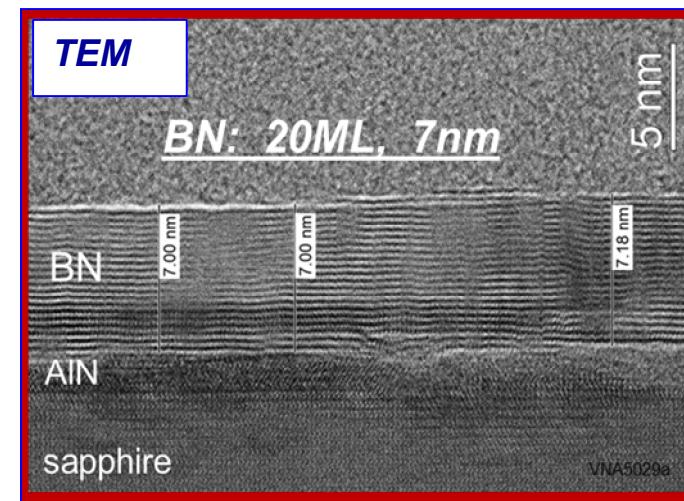
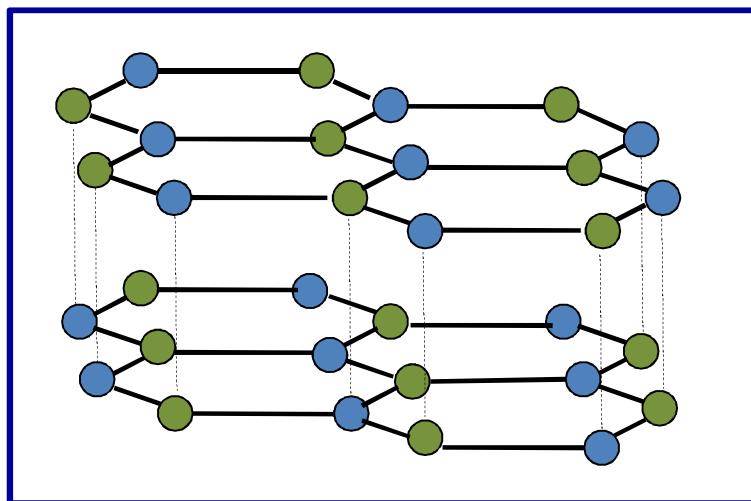


Properties of Hexagonal BN Grown by High-Temperature Metal-organic Vapor Phase Epitaxy

M. Crawford, A. Rice, A. Allerman, T. Beechem, T. Ohta, D. Medlin, C. Spataru, J. Figiel, M. Smith

Sandia National Laboratories, Albuquerque, NM 87185



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Outline

1. INTRODUCTION

- a) Background and motivation
- b) Excitonic properties

2. EPITAXIAL GROWTH AND CHARACTERIZATION OF hBN

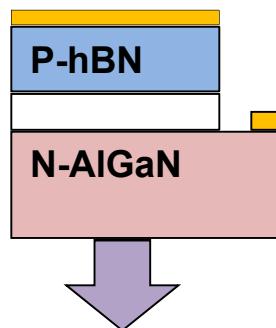
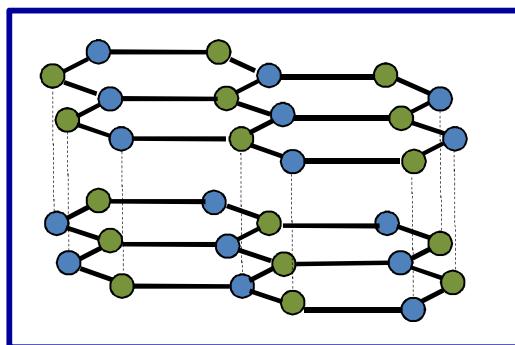
- a) MOVPE Growth at $\leq 1200^{\circ}\text{C}$
 - Pulsed growth conditions
 - Structural and optical properties
- b) MOVPE Growth at $1200 - 1700^{\circ}\text{C}$
 - Excitonic properties vs. growth temperature
 - Growth control to the monolayer limit (expt. and model)
 - Alternative substrates to sapphire
 - Alternative precursors

3. SUMMARY

Background

Motivation

- Ideal template for high-mobility graphene
- Very wide bandgap 2D material (deep UV)
- Demonstrated p-type doping
- ~ > 10x exciton binding energy of GaN

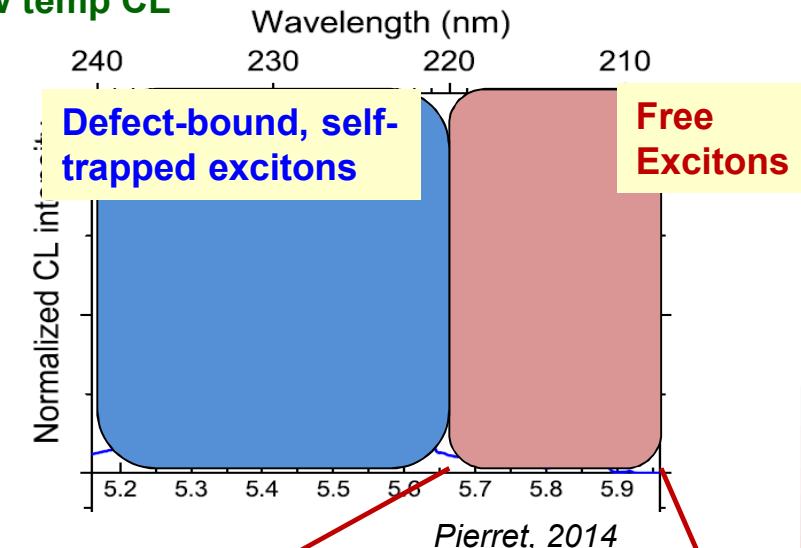


Outstanding Questions for Epitaxy:

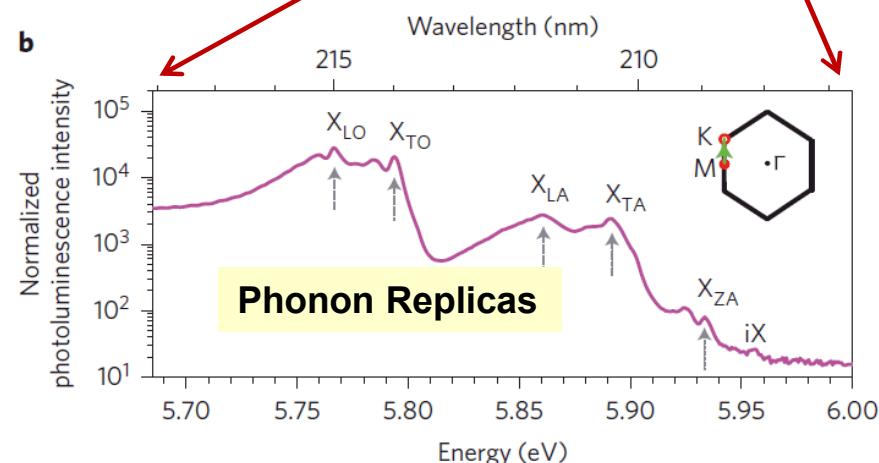
- Can we demonstrate large-area hBN with high quality surfaces for 2D heterostructures?
- Can we demonstrate ML to few-ML thickness control?
- Can we observe free-exciton-related emission at room-temperature?

Excitonic Properties

Low temp CL

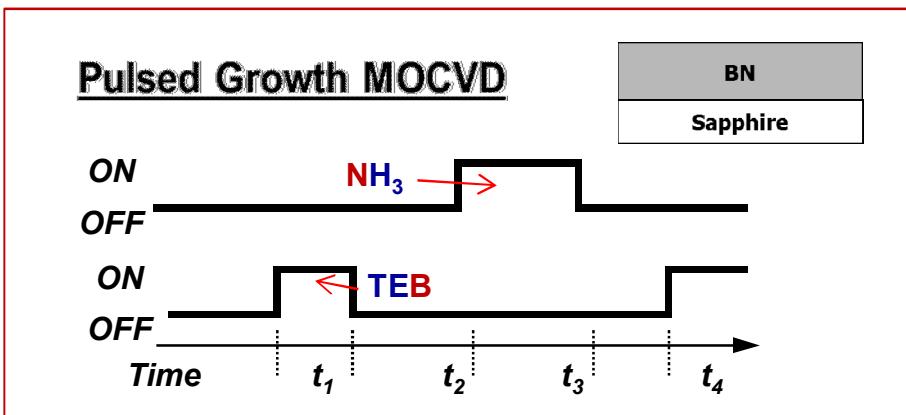


b



MOVPE Growth ($T_g \sim 1175^\circ\text{C}$)

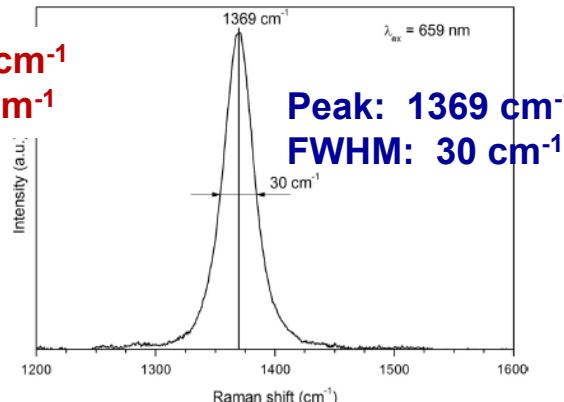
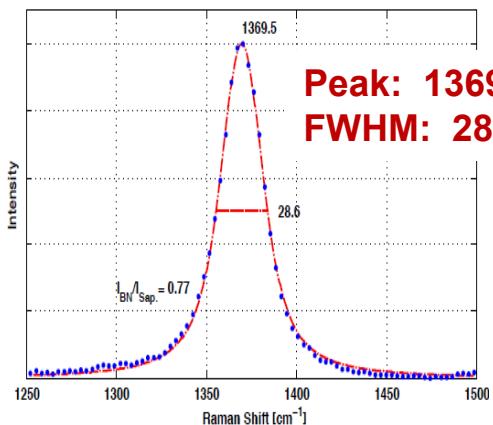
- **Continuous growth:** high growth rate at low V/III but poor crystalline quality
- **Pulsed growth** chosen to enable higher V/III ratios for improved film quality



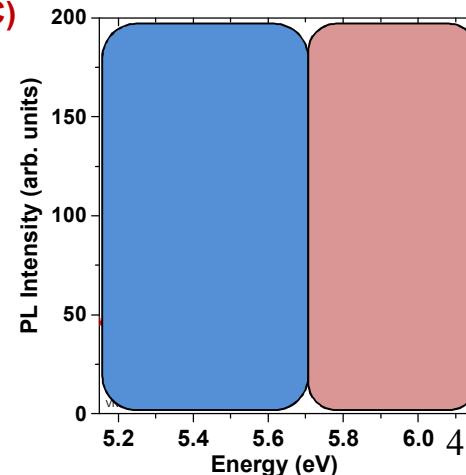
| Growth Condition | Parameter Range |
|--------------------|----------------------------|
| Temperature | 1175°C |
| Pressure | 50-200 Torr |
| NH_3 Flow | 0.2-10 slm |
| TEB Flow | 3-12 $\mu\text{moles/min}$ |
| Pulse Cycles | 20-9600 |
| Time per Cycle | 1-12 sec |

Raman Spectra

Compare to Chuborov 2014 (1500°C)

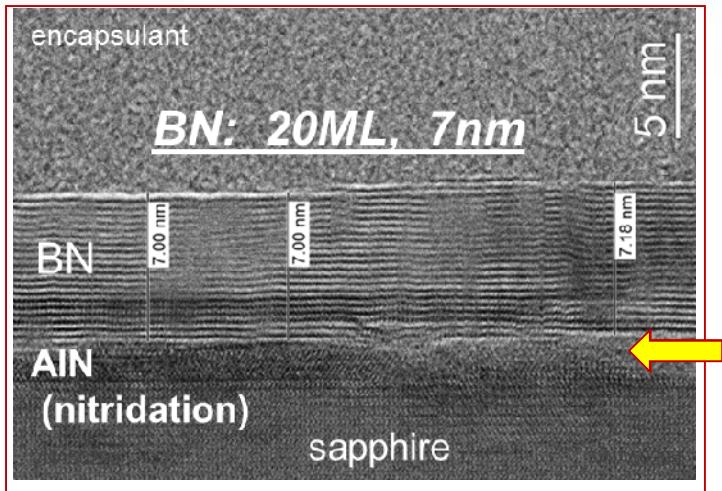


Room Temp PL

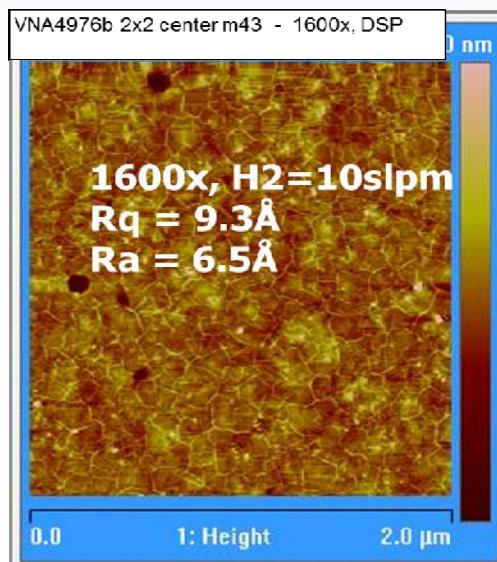


Structure and Morphology of hBN ($T_g \sim 1175^\circ\text{C}$)

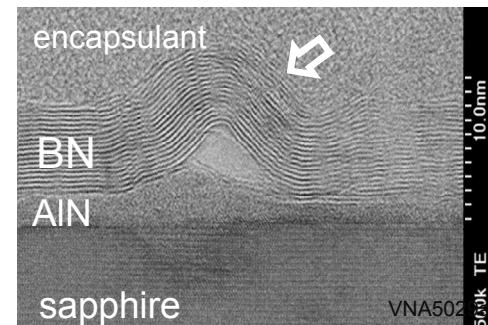
High-resolution cross-section TEM



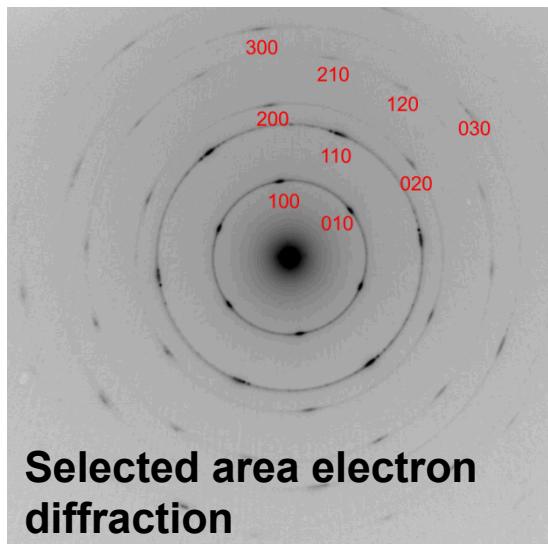
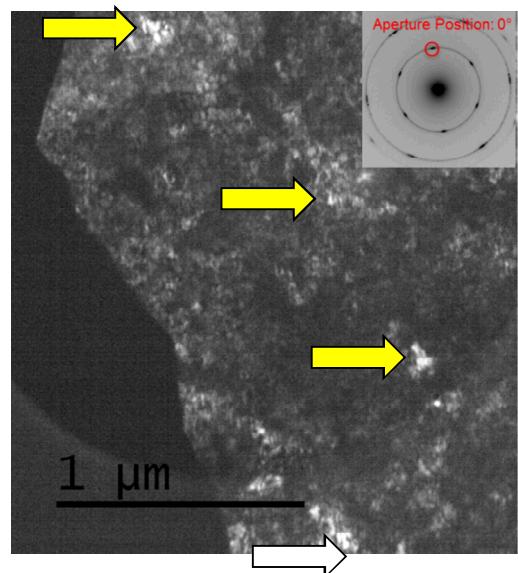
AFM



- Typical “wrinkles”
- Also particles forming on surface with increasing thickness



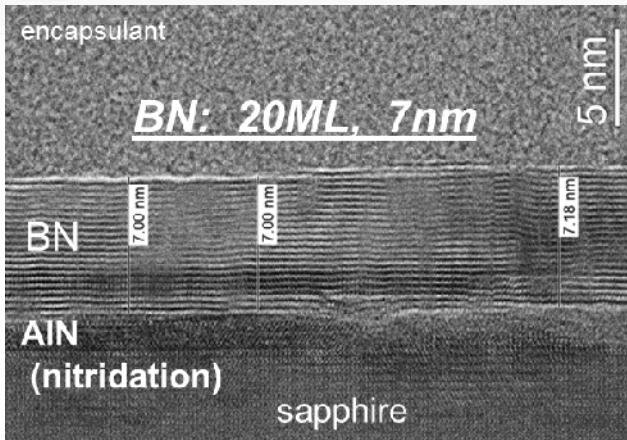
TEM (dark-field) free-standing BN



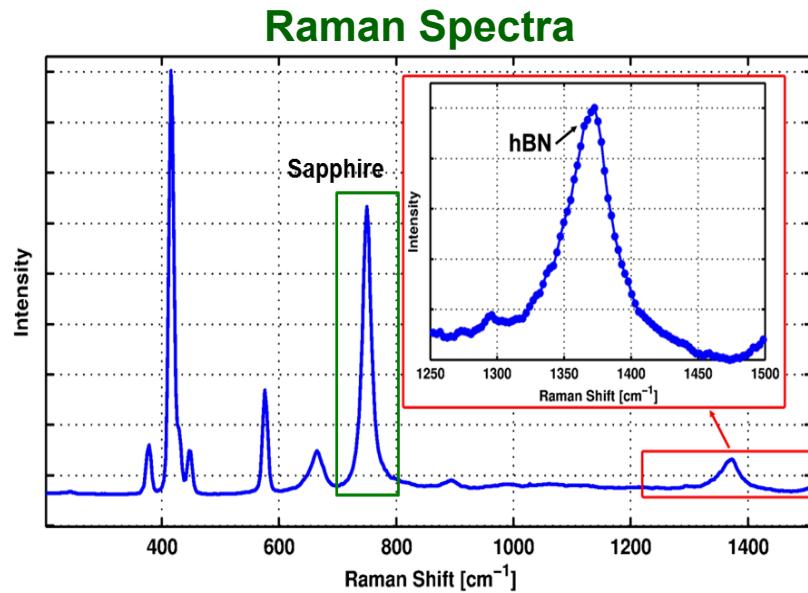
- Bright regions indicate strong in-plane alignment
- $hk0$ rings indicate in-plane rotation disorder
- $hk0$ reflection spots indicate basal plane alignment

Estimation of Film thicknesses: Raman

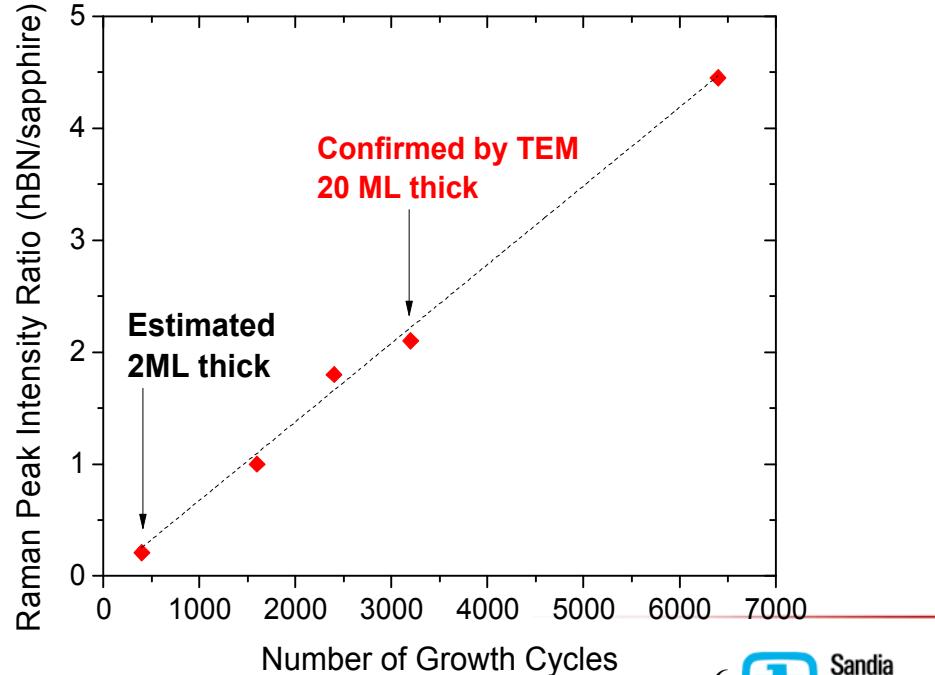
Cross-sectional TEM



- Difficulty seeing very thin layers by TEM
- Using hBN/sapphire Raman intensity ratio, calibrated to TEM of thicker films, as a rough estimate of thickness
- Suggests reproducible 1-3 ML control

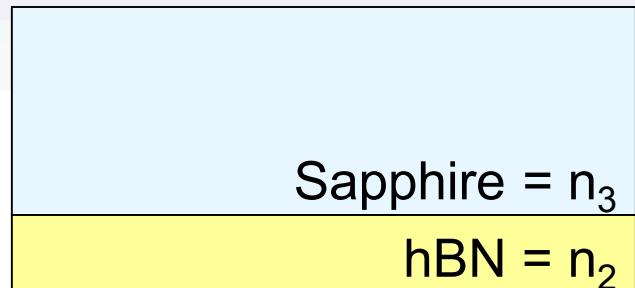
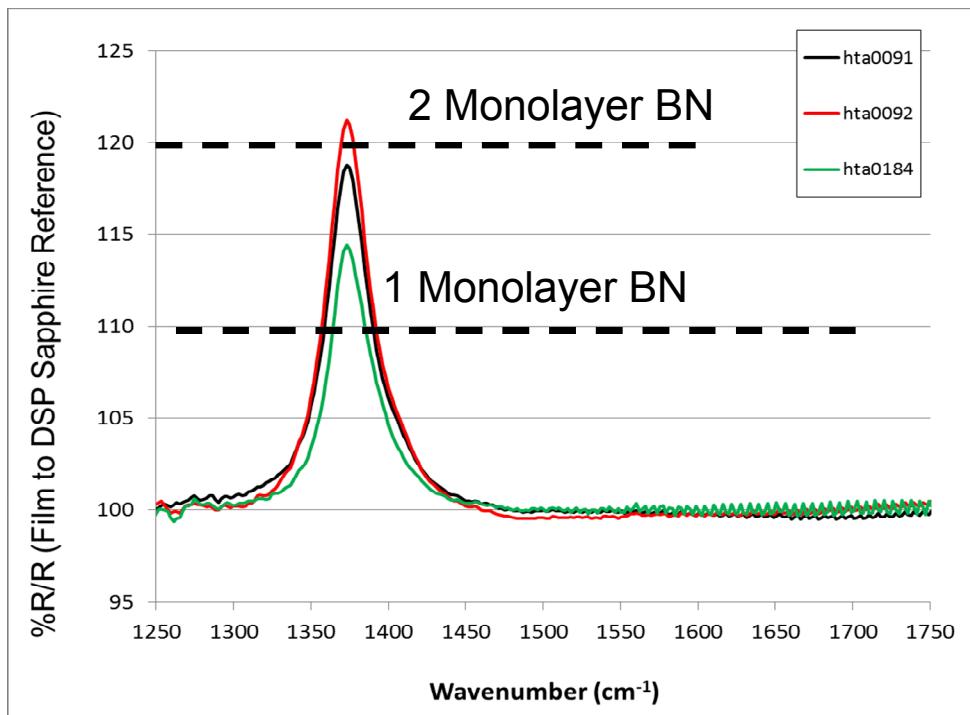


BN Raman peak ratio (I_{BN}/I_{sapp}) vs. Pulse Cycles



Estimation of Film thicknesses: FTIR

- Take advantage of the large difference between BN and sapphire extinction coefficients
- Apply 3-layer differential reflectance model
- Yields $\Delta R/R \sim 110\%$ for $d = 1$ ML
- Averages for partial coverage



$$\frac{\Delta R}{R} = \frac{8\pi d n_1}{\lambda} \text{Im} \left(\frac{\hat{\epsilon}_2 - \hat{\epsilon}_3}{\epsilon_1 - \hat{\epsilon}_3} \right)$$

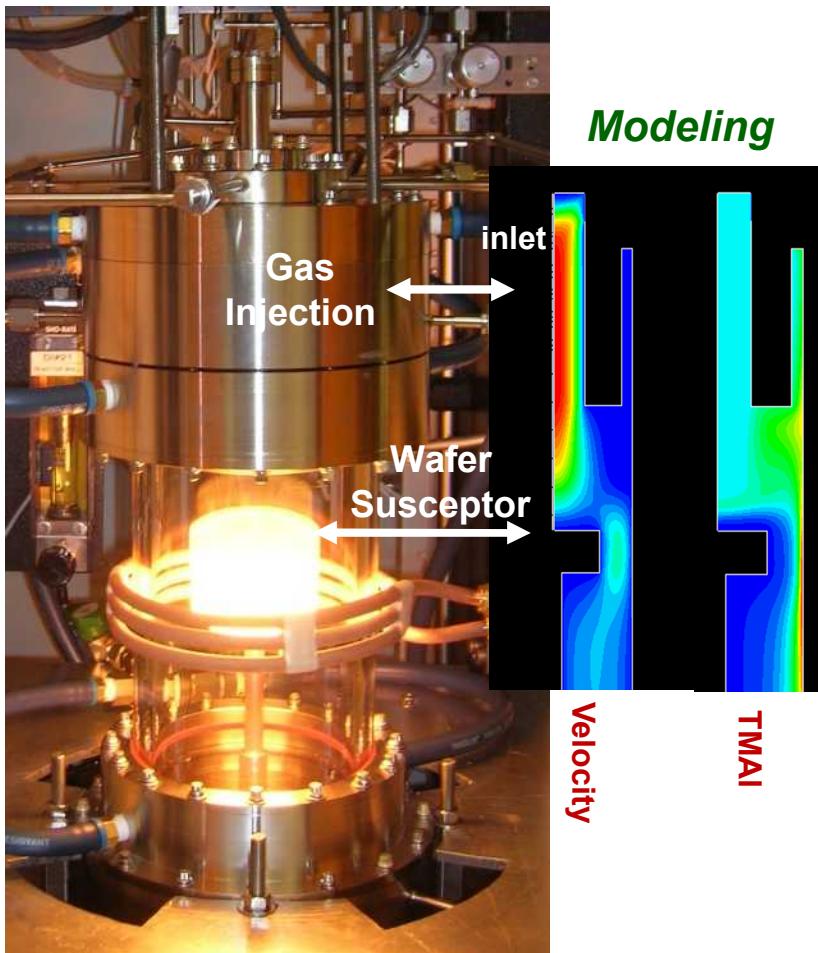
McIntyre and Aspnes., 1971

R. Creighton, SNL

- hBN films between 1 and 2 monolayers by Raman
- Two techniques give similar results, FTIR more consistent

High Temperature MOVPE

>1800°C Operation

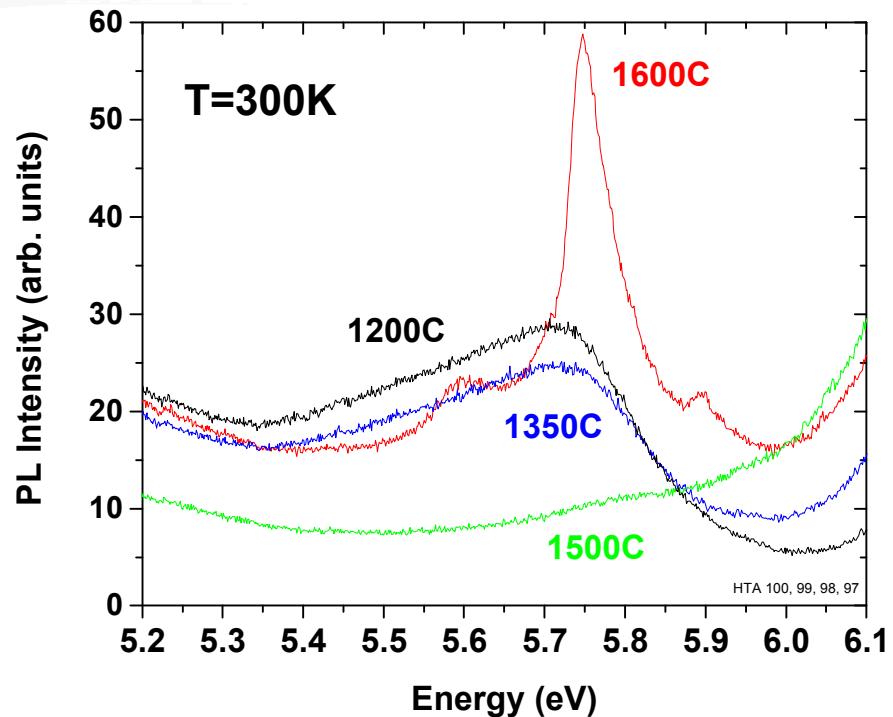


- **Advantages of HT growth**
 - Increased surface mobility of Group-III atoms.
- **Continuous Growth (TEB + NH₃)**
 - Temperature: 1200 – **1600** - 1800°C
 - Pressure: 50 torr
 - NH₃: 0.1 – **2** - 5 slpm
 - TEB: **12** μ moles/min
 - Carrier gas: **N₂**
 - H₂: **0** – 5 slpm

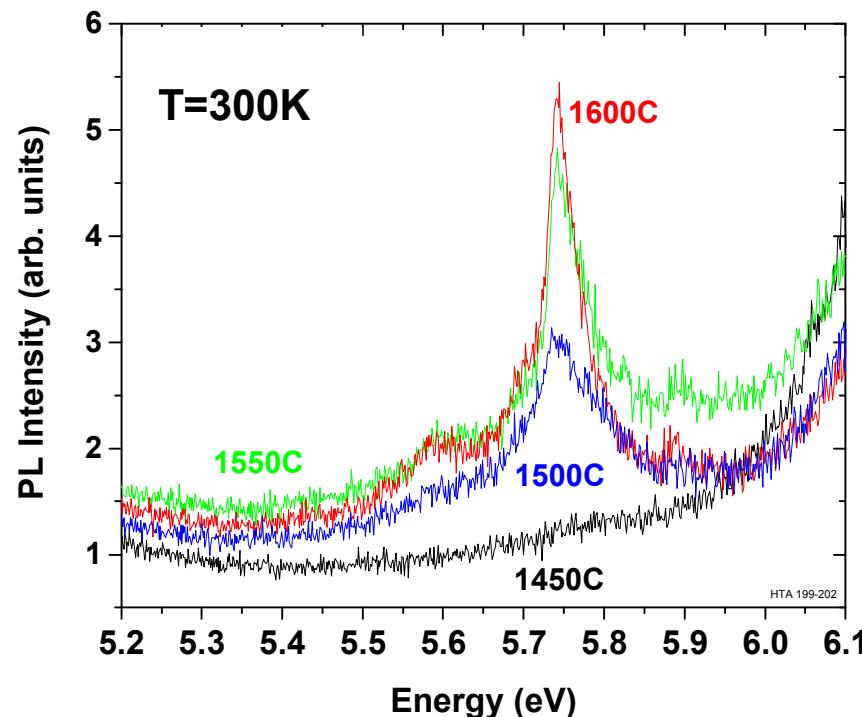
Reactor Design from Prof. Zlatko Sitar (NC State)

Growth Temperature Study: PL

Wide Temp Range: $T_g = 1200\text{-}1600^\circ\text{C}$

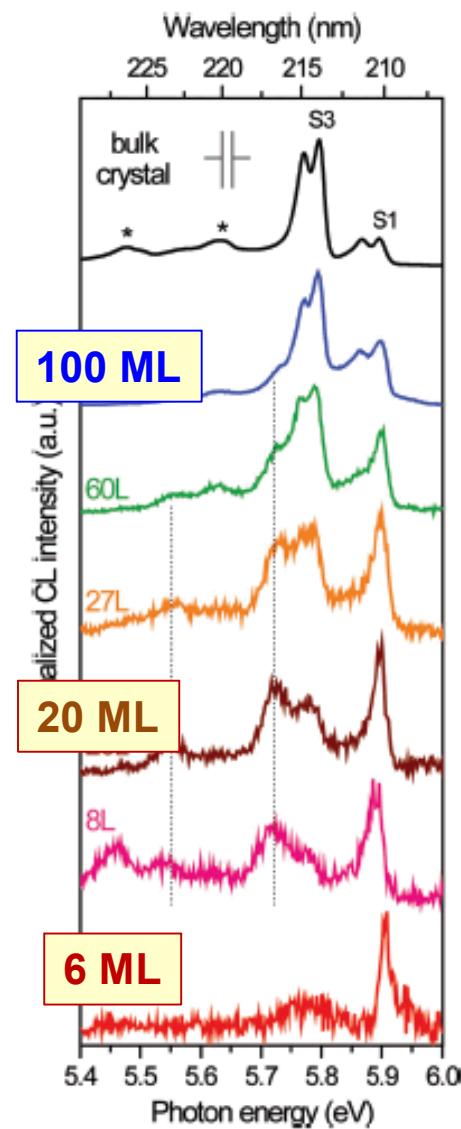
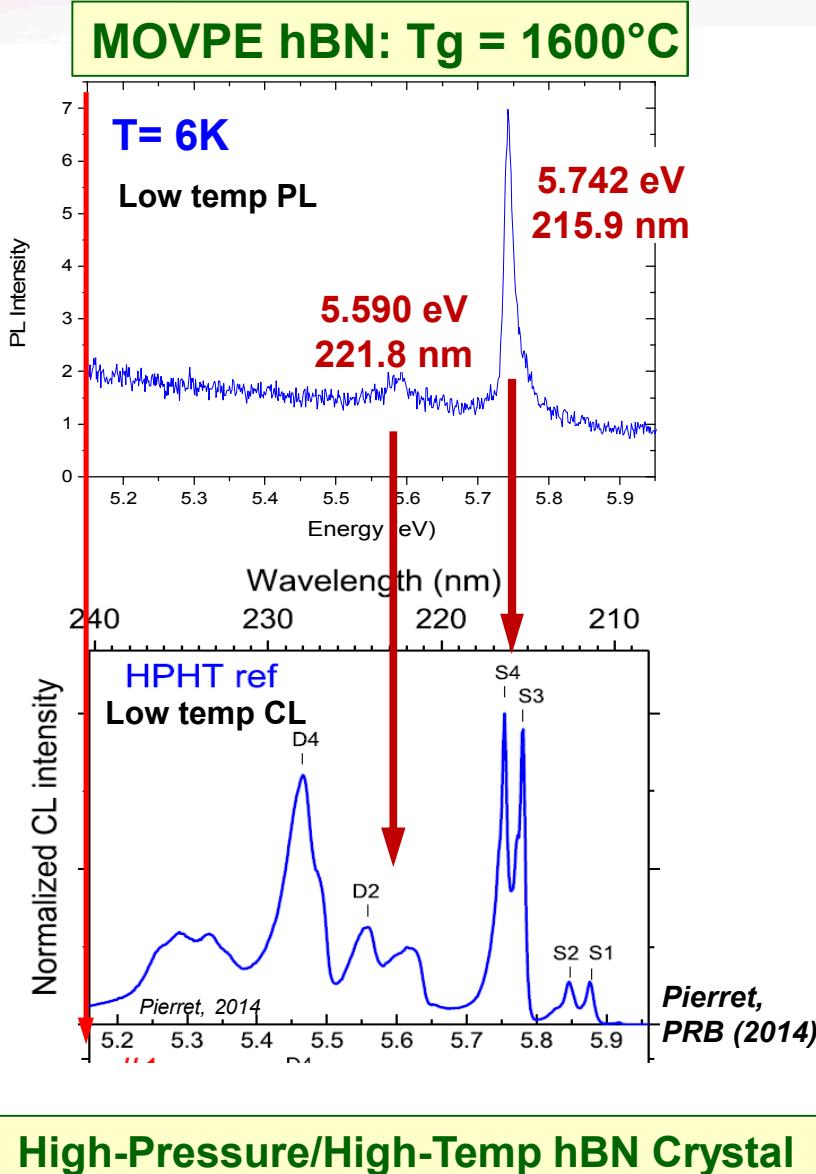


Transition Region: $T_g = 1450\text{-}1600^\circ\text{C}$



- Unusual evolution of near-band-edge features with increasing growth temperature
- Transition to sharp higher-energy free-exciton peak at $T_g \sim 1500\text{-}1600^\circ\text{C}$
- Observation of room temperature free (5.75 eV) exciton in MOVPE hBN

Low-Temperature Luminescence: Comparisons with Bulk and Exfoliated hBN



Exfoliated hBN Flakes

Low temp CL
Schue, *Nanoscale* (2016)

→ Excitonic signatures of few ML MOVPE hBN similar to that of best exfoliated samples from high-quality hBN crystals

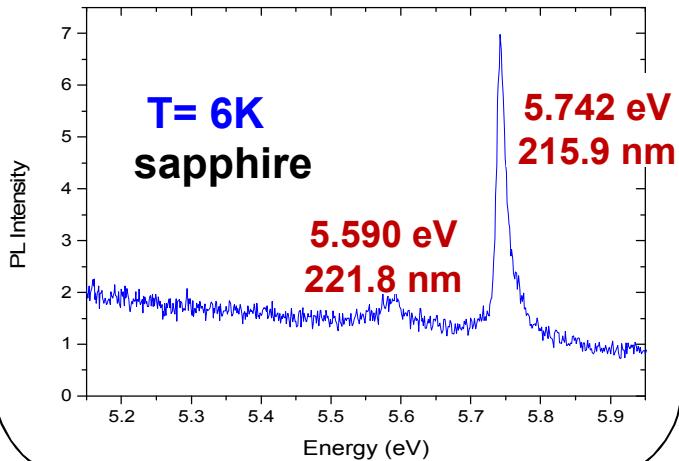
- Evolution to 1 dominant peak (S1) near 5.9 eV with thinner exfoliated layers
- Few-ML MOVPE sample dominated by 5.75 eV peak (S4)

Low-Temperature Luminescence: Comparisons with other Epitaxially-Grown hBN

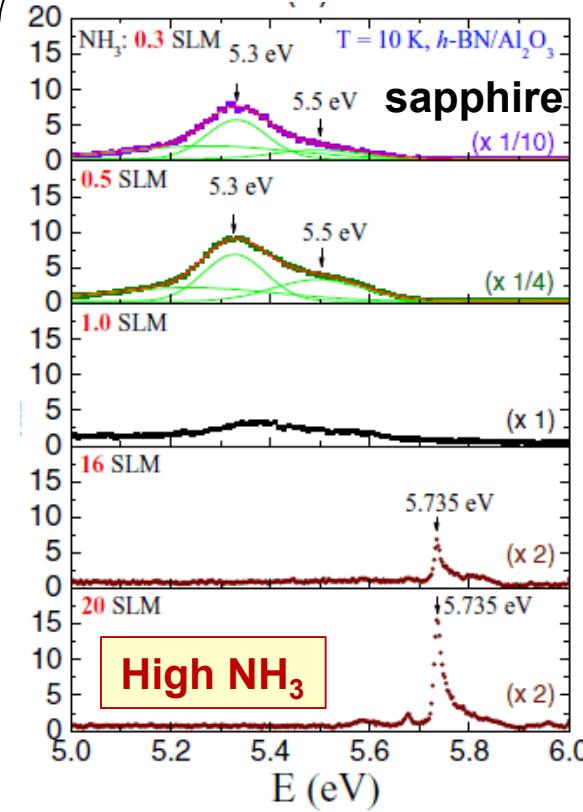
MOVPE: High temp or moderately high temp and high NH_3 yields dominant ~ 5.74 eV peak

MBE: Moderately high temp yields higher energy ~ 5.9 eV peaks on HOPG

MOVPE hBN: $T_g = 1600^\circ\text{C}$

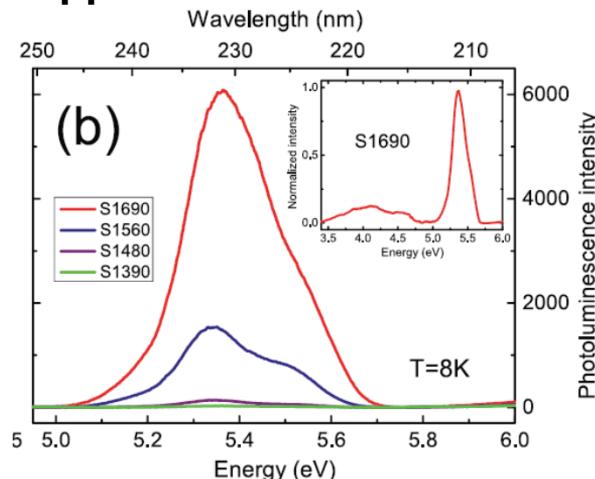


MOVPE hBN: $T_g = 1350^\circ\text{C}$

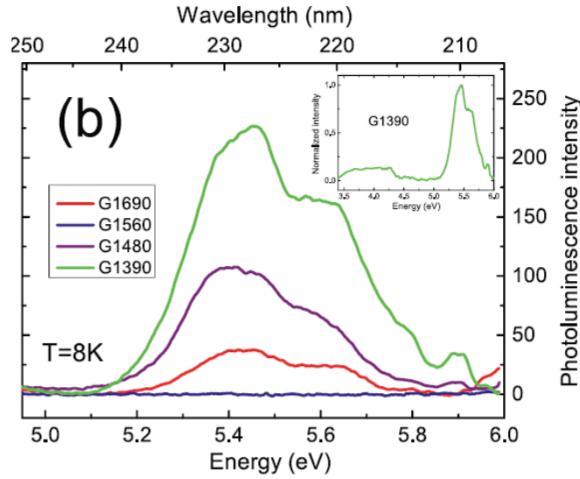


sapphire

MBE hBN: $T_g = 1390-1690^\circ\text{C}$

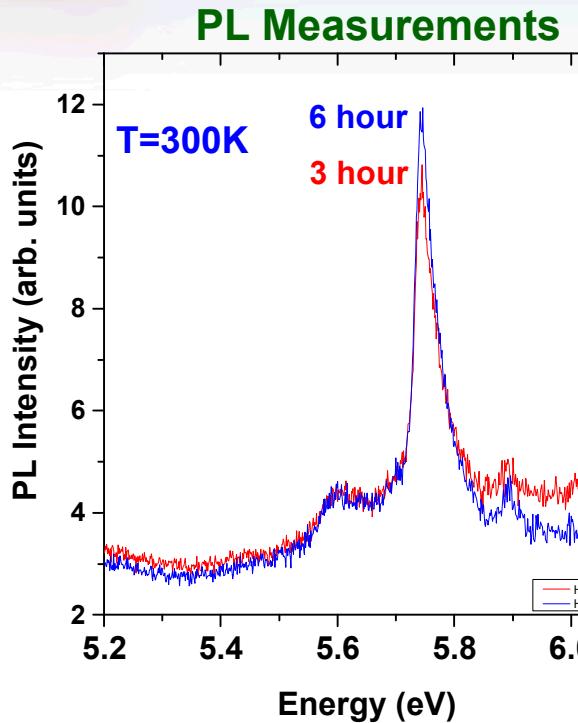


HOPG



Vuong et al. 2D Mat 2017

Potential for Self-limiting Growth at high T_g

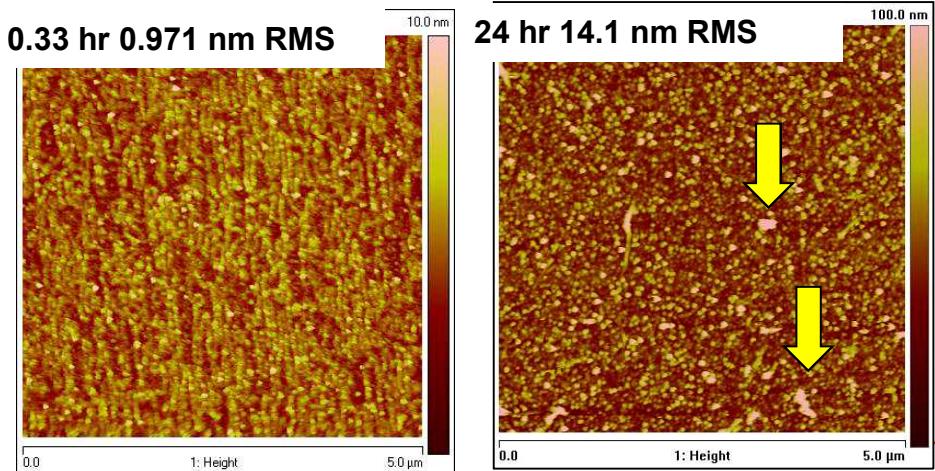


- Relatively little change in PL intensity over a large range of growth times
- Raman ratio (hBN/Sapphire) suggests only a few MLs even for 24 hours of growth
- Films roughen, largely due to increased number of larger particulates with longer growth times

Results from Raman Measurements

| Growth Temp (°C) | Growth Time (hrs) | Raman peak ratio | STEM calibration (MLs) |
|------------------|-------------------|------------------|------------------------|
| 1600 | 0.25 | 0.1 | ~1 |
| 1600 | 3 | 0.09 | ~1 |
| 1600 | 3 | 0.18 | ~2 |
| 1600 | 6 | 0.16 | ~2 |
| 1600 | 24 | 0.26 | ~3 |

AFM Measurements

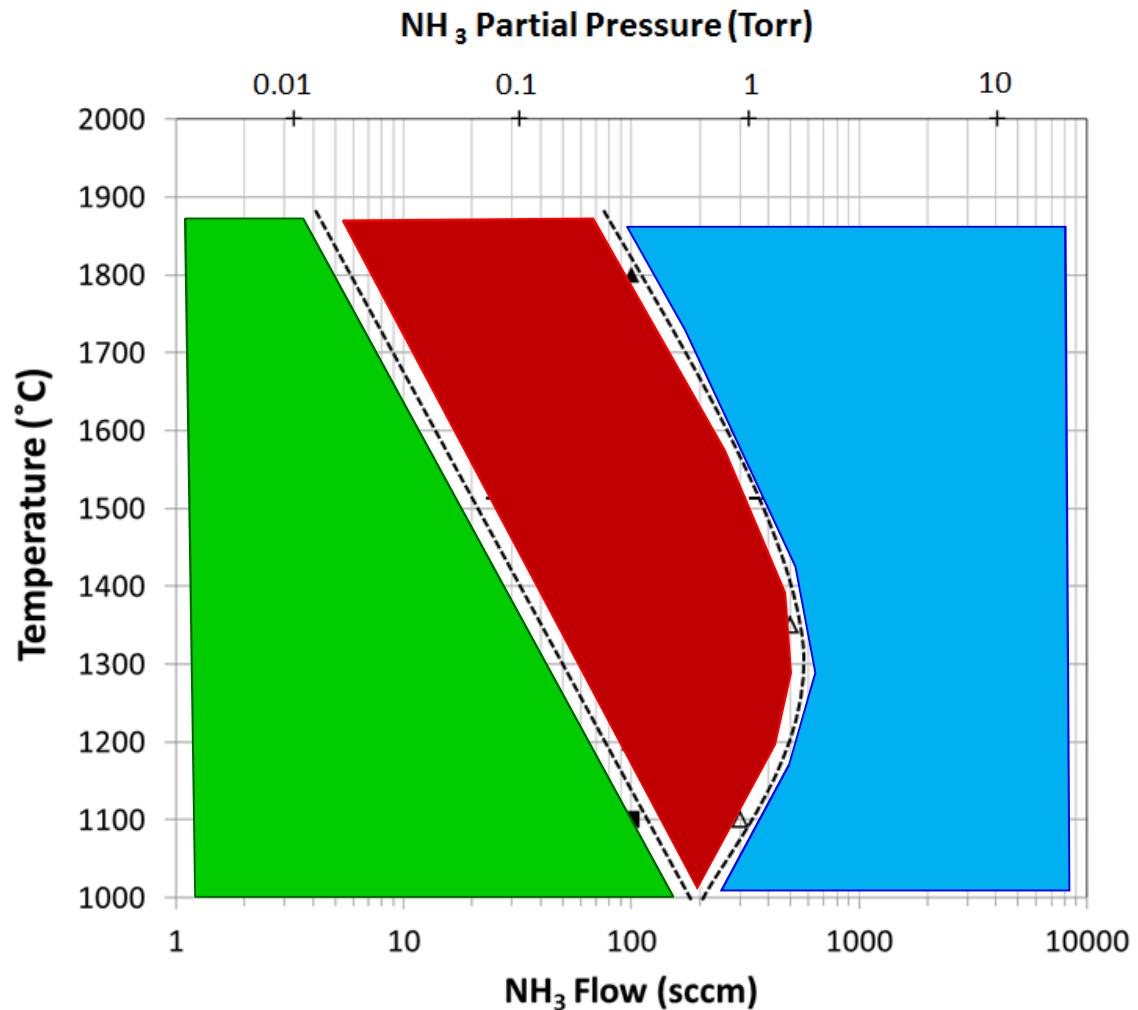


Growth parameter space for achieving few-ML-thick films

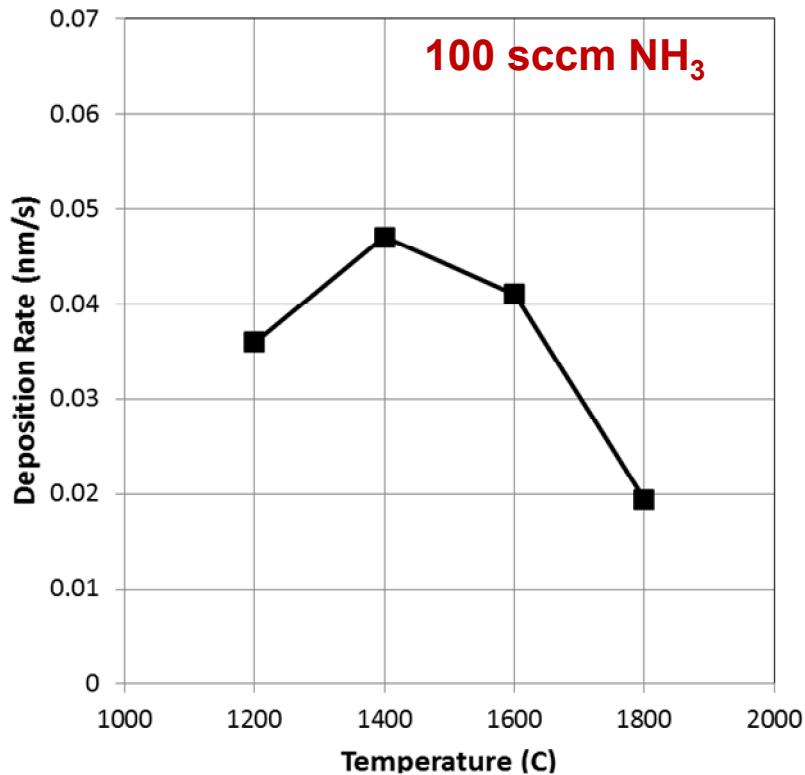
→ Focus on Growth Temperature and NH_3 flow

Growth Regimes

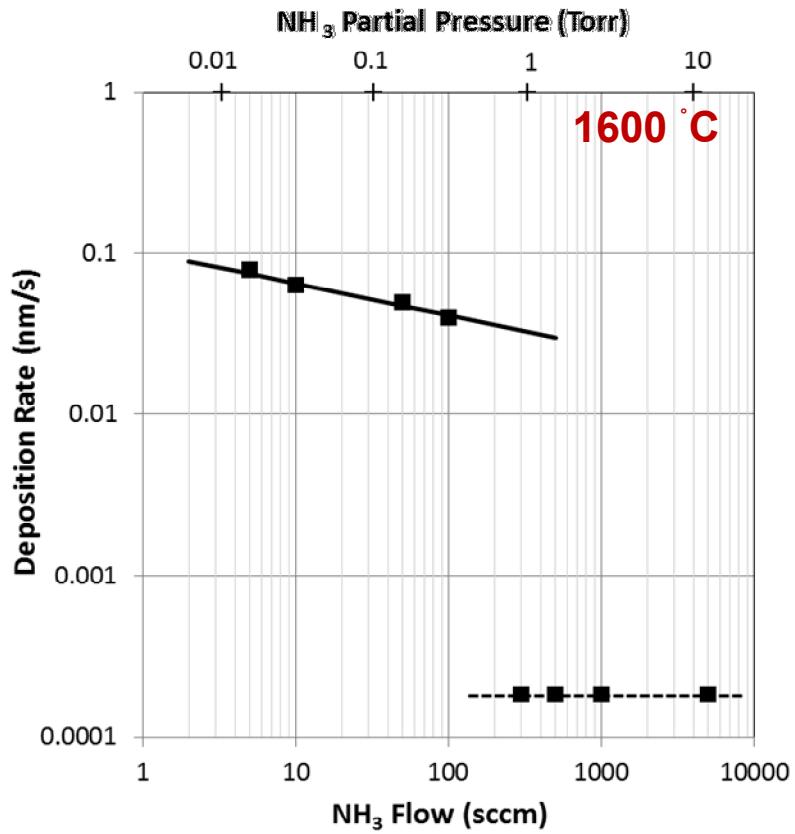
- Low NH_3
 - Thick films
 - Discolored films
- Intermediate NH_3
 - Thick films
 - Clear films
- High NH_3
 - Self-limiting films



Growth rate studies to evaluate self-limiting mechanism



- Growth rate is weakly temperature dependent
- ~2.5x change over 600 °C

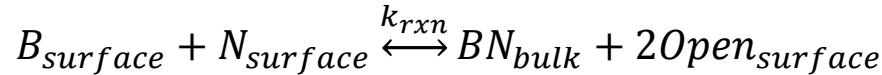
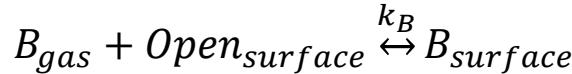


- Critical NH_3 threshold exists for all temperatures
- 2-3 orders of magnitude change in growth rate

→ Trends not consistent with parasitic reactions

Possible Model: Langmuir-Hinshelwood

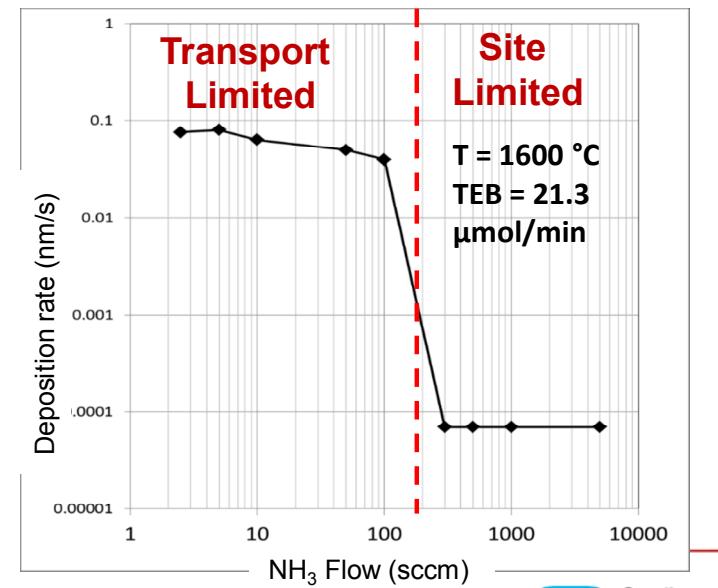
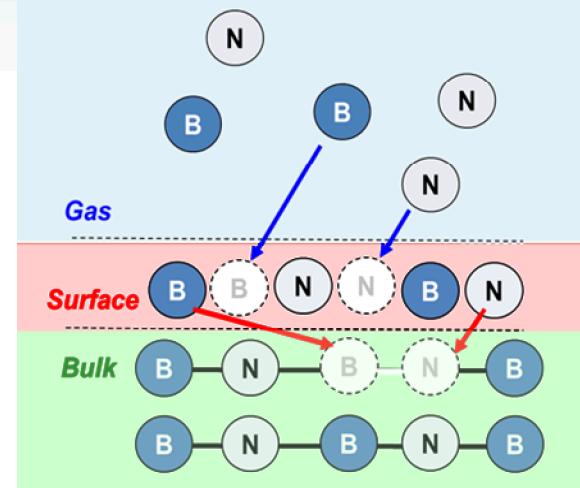
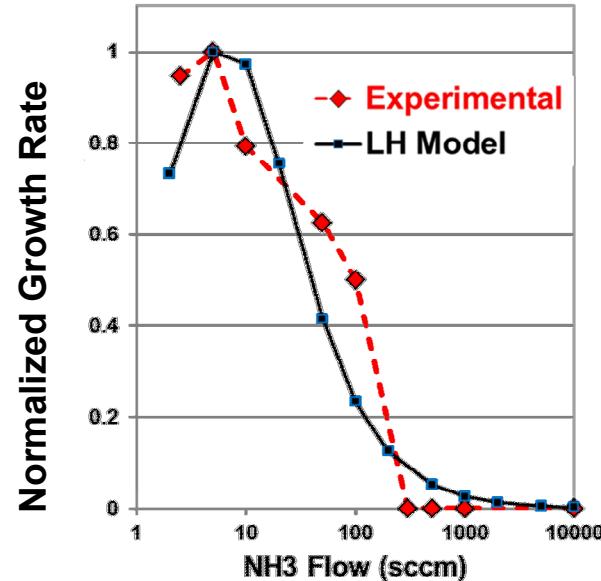
- Competitive absorption of species that react on a surface
- Controlling reactions:



- Growth rate:

$$G = \frac{k_{\text{rxn}} k_B k_{NP} p_B p_N \Gamma^2}{(1 + k_B p_B + k_N p_N)^2}$$

Model captures large decrease in growth rate from microns to monolayers per hour

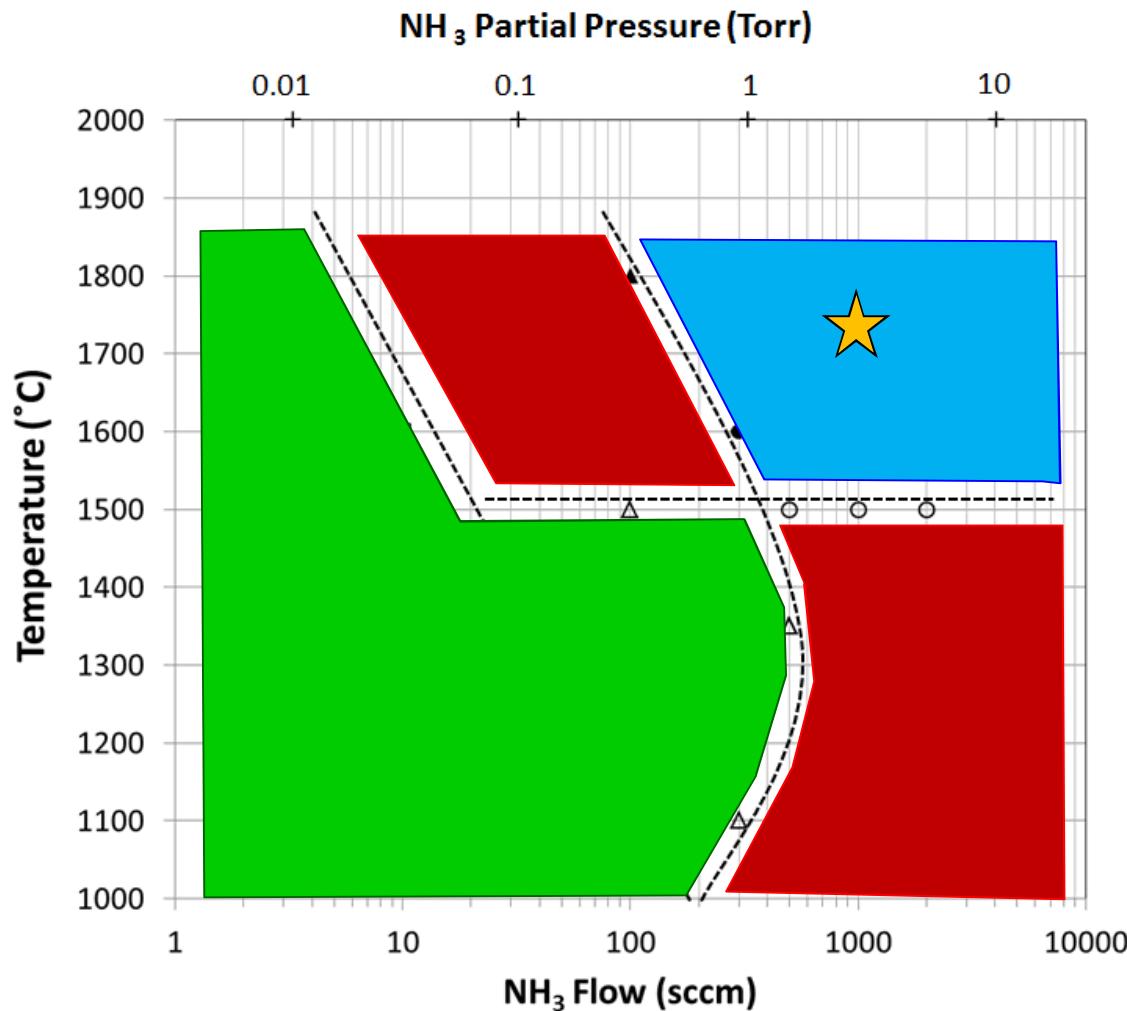


Correlation of Growth Conditions and Excitonic Performance

3 regimes in room temp PL

- No exciton emission
- Defect bound exciton
- Free exciton

RT PL

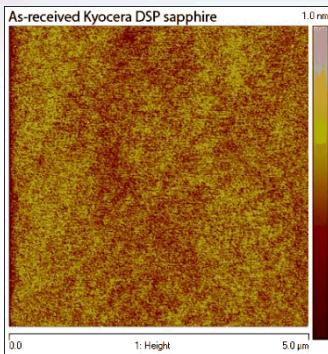


High NH₃ and high temperature for RT excitons

Challenge with High Temp Growth: Nitridization of Sapphire Substrate

Sapphire Substrate

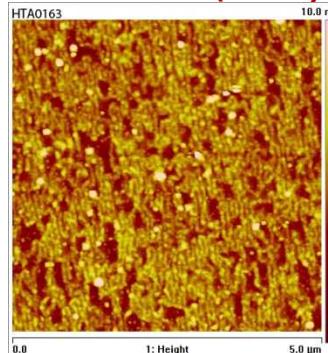
0 min
> 0.1 nm
RMS



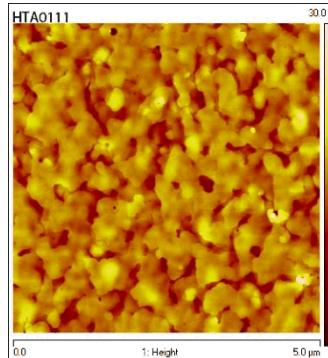
Nitrided Sapphire Substrate

1600°C NH₃ but **No Boron Source Material (TEB)**

5 min
1.17 nm
RMS

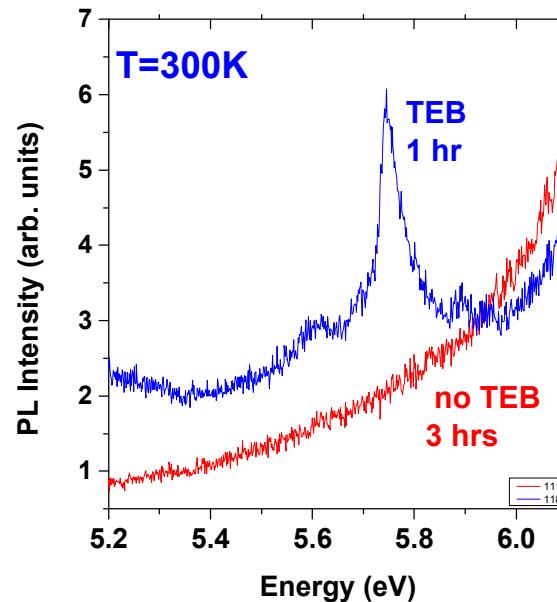


180 min
2.71 nm
RMS

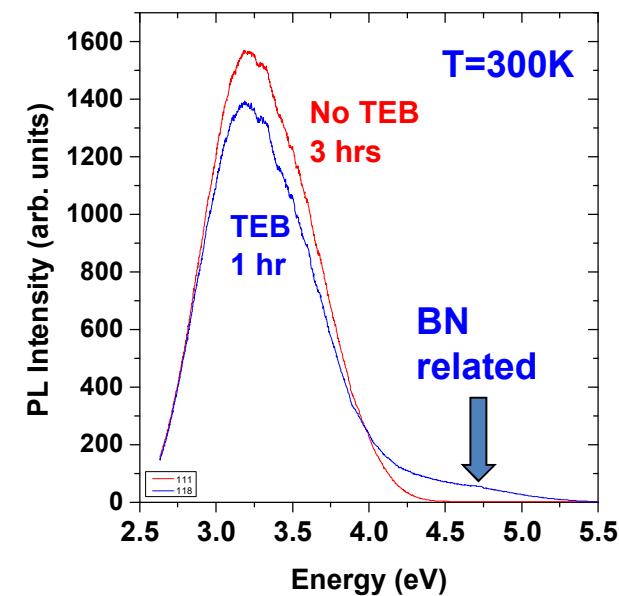


PL comparison: BN on Sapphire vs. Nitrided Sapphire

Near Band Edge



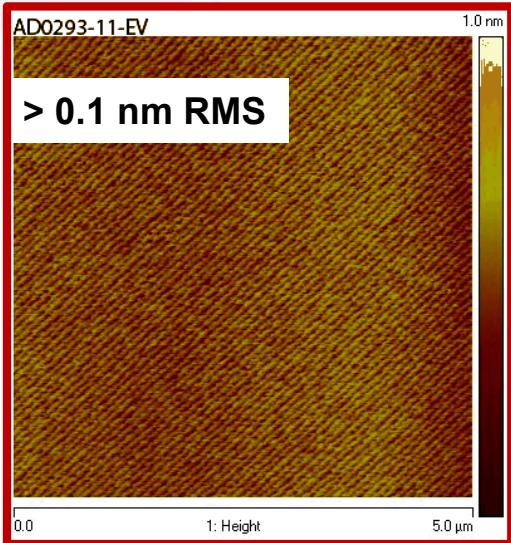
Deep Level



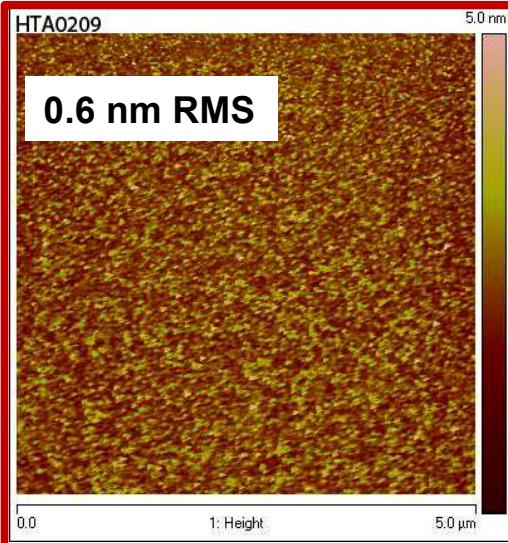
- High temperature NH₃ exposure causes nitridization of sapphire surface (AlN peak seen by Raman)
- Lower crystalline quality than original sapphire, impacts BN morphology
- Contributes strong deep level emission at ~ 3.2 eV

Alternative Substrates: SiC

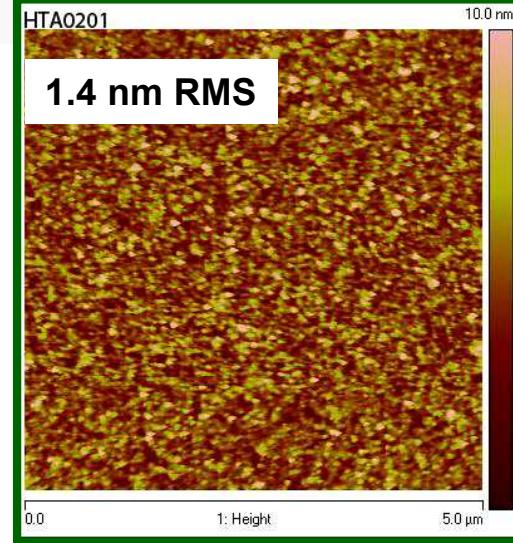
As-received SiC



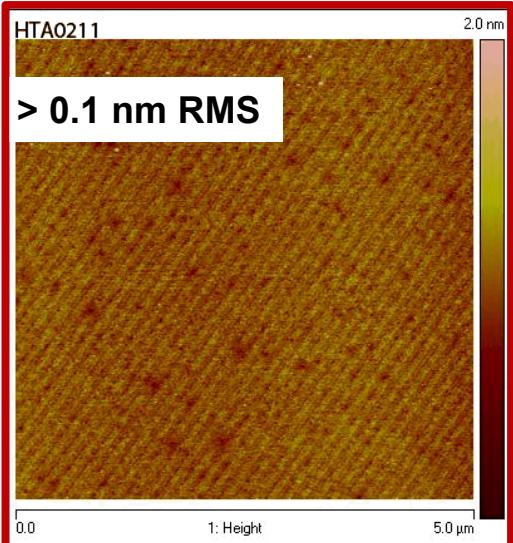
1600°C BN on SiC



1600°C BN on Sapphire



1600°C NH₃ treatment, no TEB



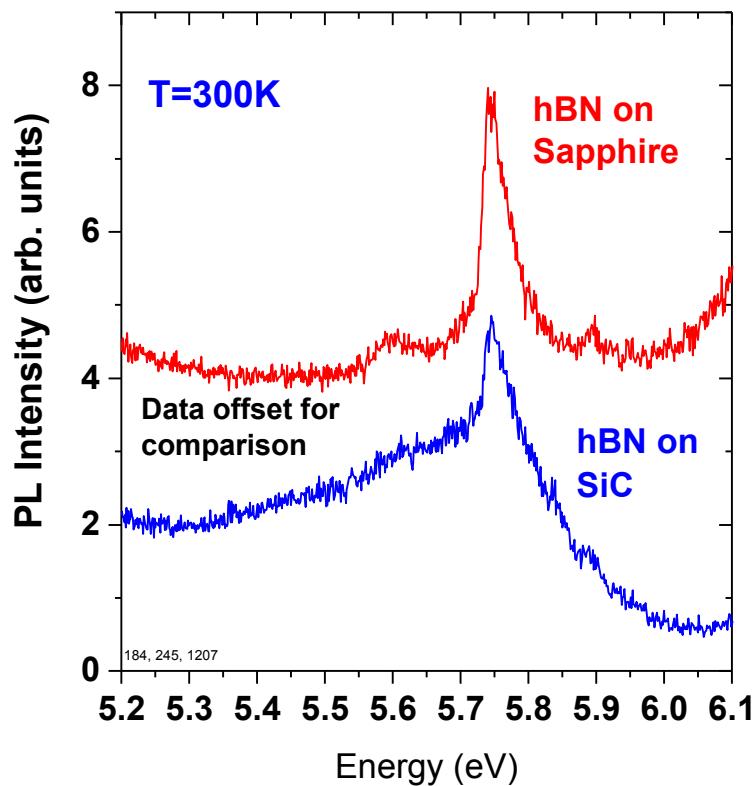
| Tg (°C) | RMS roughness (nm) |
|---------|--------------------|
| 1400 | 0.7 |
| 1500 | 0.4 |
| 1600 | 0.6 |

Growth Conditions: 50 Torr, 25 sccm TEB, 2 SLM NH₃, 1 hour

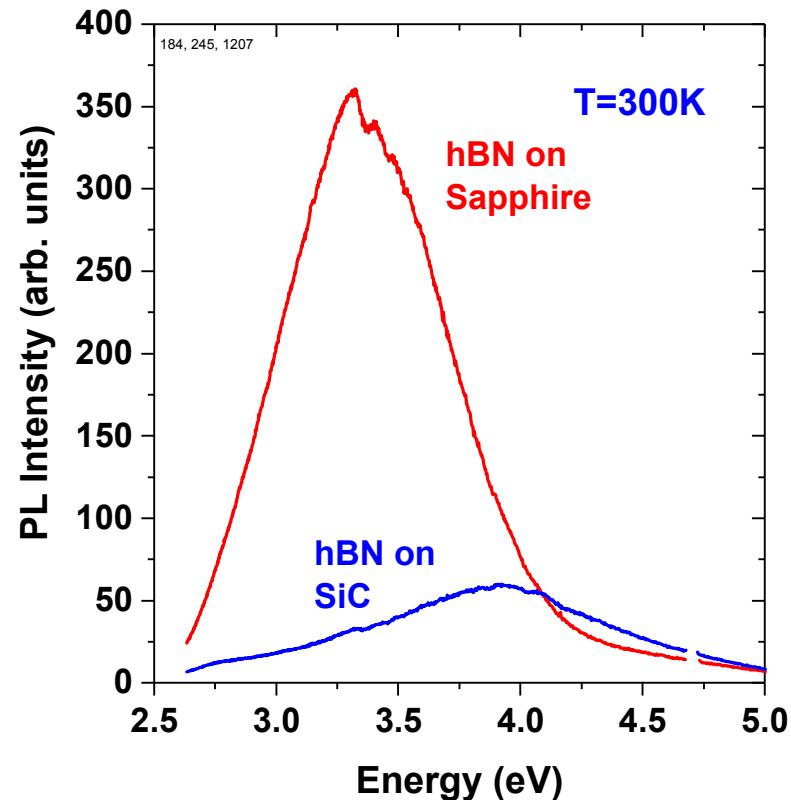
- SiC surface relatively stable with NH₃ exposure
- BN roughness improved over sapphire

hBN on SiC: Luminescence Properties

Near Band Edge PL



Deep Level Emission

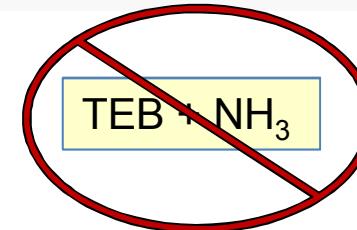


- Observe 5.75 eV excitonic peak in room-temp PL, not as well defined as on sapphire
- Elimination of deep level peak associated with nitrided sapphire

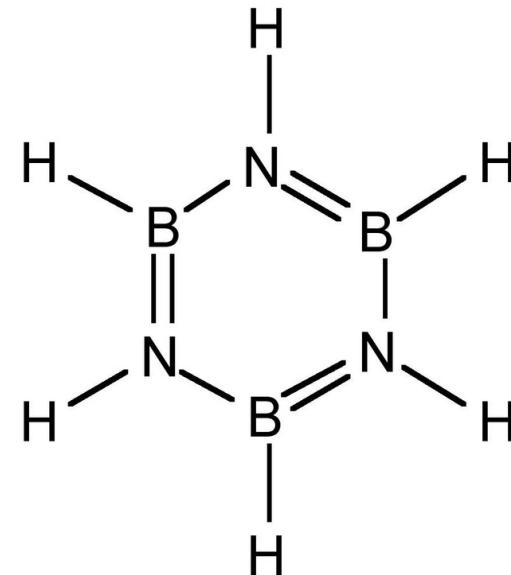
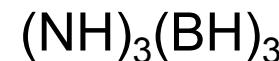
Borazine to reduce sapphire substrate degradation at high temperature

Pros

- Literature reports of BN deposition
- High vapor pressure
- Liquid source
- Single source growth



Borazine

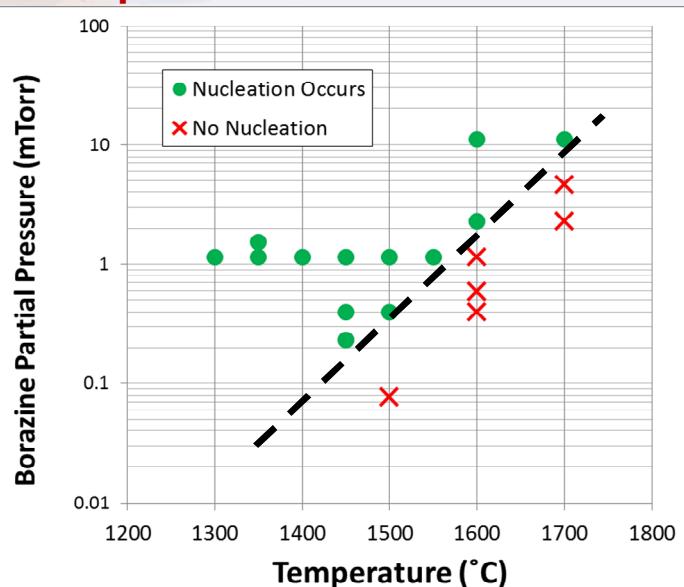


Cons

- Literature reports are mostly on metal
- Stability and purity of source
- Single source growth, e.g., no independent control of V/III ratio

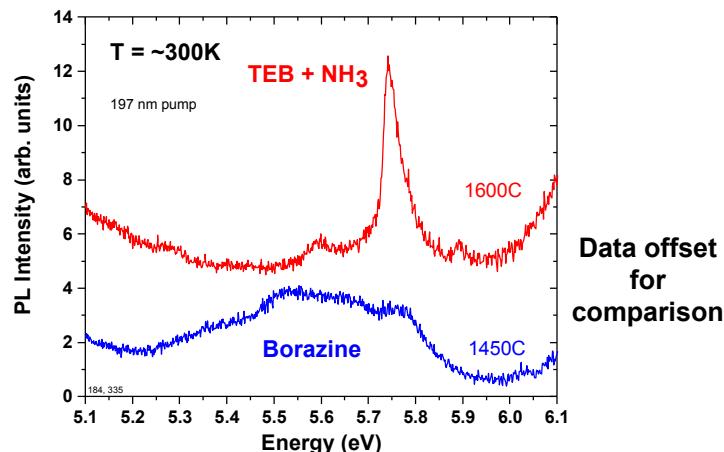
hBN on Sapphire using Borazine

Epitaxial Growth Studies



- Critical borazine partial pressure for nucleation
- Strong function of growth temperature

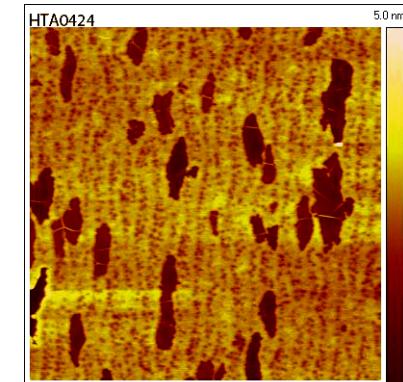
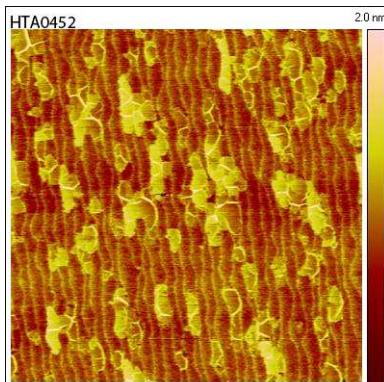
Photoluminescence (~300K)



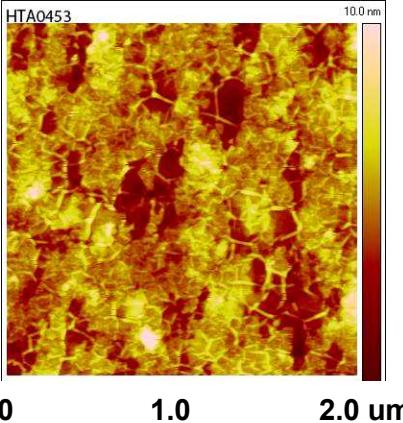
Characteristic Morphologies (AFM)

≤ 1 ML
RMS roughness ~ 0.2 nm

$1 - 3$ MLs
RMS roughness ~ 0.5 nm



≥ 3 ML
RMS roughness > 1 nm



- Morphology largely determined by thickness
- Not a strong function of borazine partial pressure or temperature



Summary

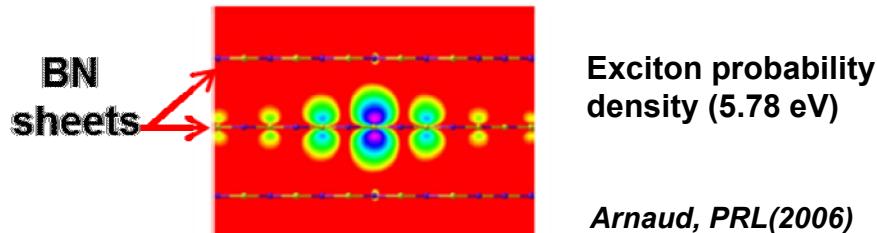
- Explored high- T_g MOVPE as an approach to achieving high-quality, few-ML-thick hBN films
- Lower- T_g films (pulsed growth) demonstrated notable in-plane rotational disorder and defect-related excitonic signatures
- Dramatic evolution of excitonic properties with T_g ; $T_g \sim 1600^\circ\text{C}$ yielded strong free exciton features similar to best exfoliated crystals
- Proposed site-blocking model to explain self-limiting growth of few ML thickness at high- T_g
- SiC substrates or Borazine precursor are promising to avoid sapphire substrate degradation at high temperatures
- Growth of few-ML-thick hBN films on sapphire using Borazine; studied nucleation, structural and optical properties

- Extra Slides

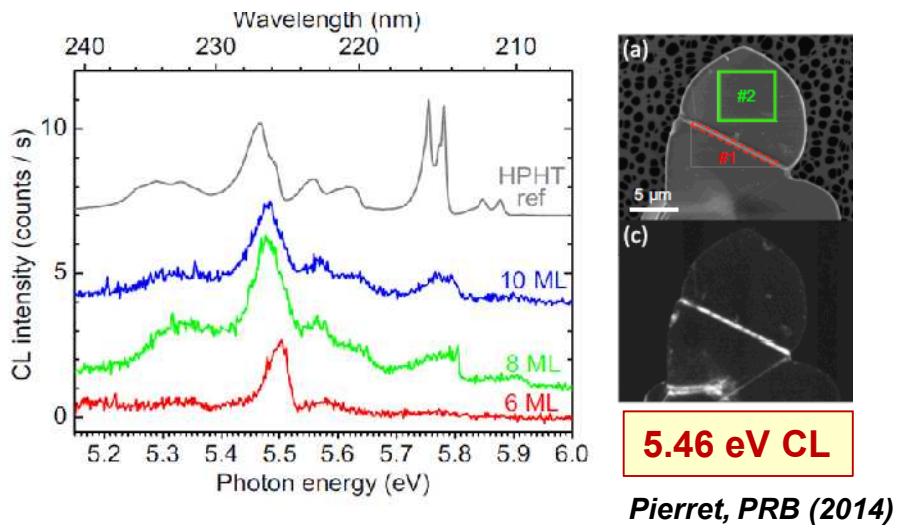
Excitonic Properties at Few-Monolayer Thickness

Question: How do the excitonic properties of hBN evolve with thickness down to 1 ML?

Strong Exciton Confinement

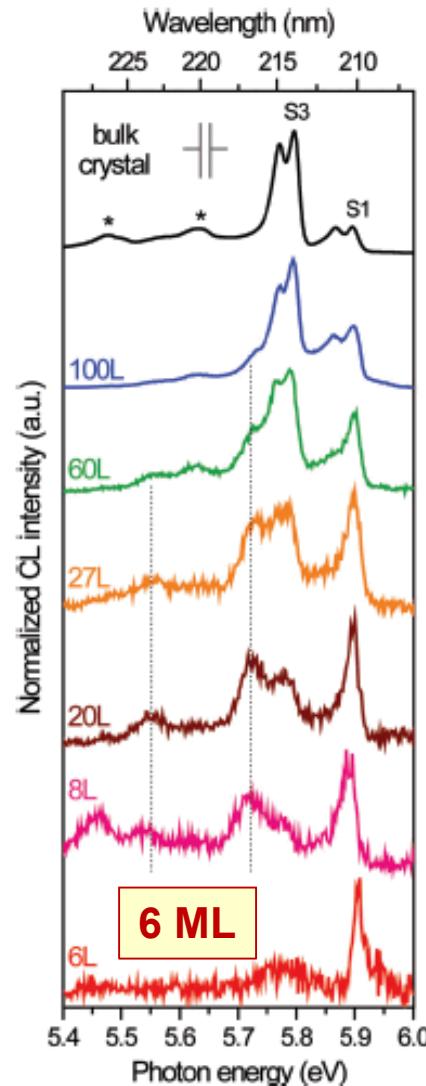


Low Temp. CL: Exfoliated hBN flakes



Loss of higher energy, free-exciton related features with exfoliation

Low Temp CL: Exfoliated hBN Flakes

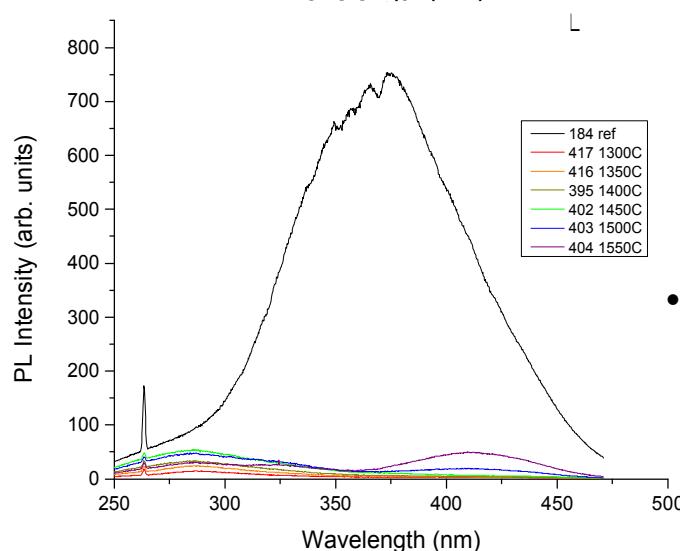
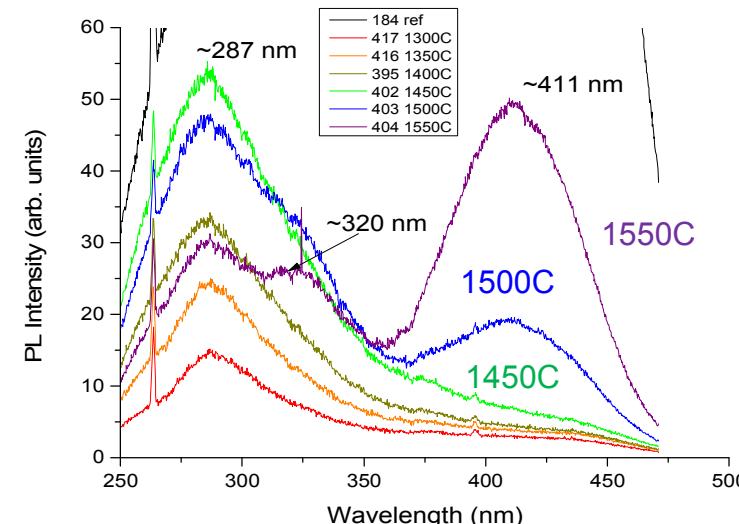
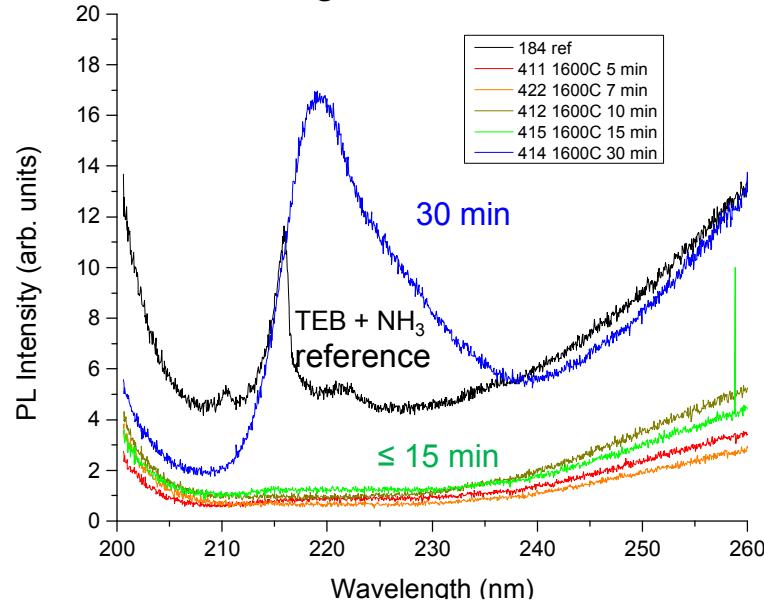


Improved Exfoliation: excitonic evolution down to 6 ML

→ Explore epitaxial growth approaches

PL variations observed for hBN using Borazine

- Longer growth times/ thicker films needed for near band-edge emission
- Deep level peaks dependent on growth temp
- Origin may be from defects in sapphire



- Nitrided sapphire deep-level peak is avoided with borazine at all growth temperatures

Nucleation Theory

- In depth study of nucleation of hBN on sapphire
- Not possible with commonly-used TEB and NH₃ sources, substrate degradation

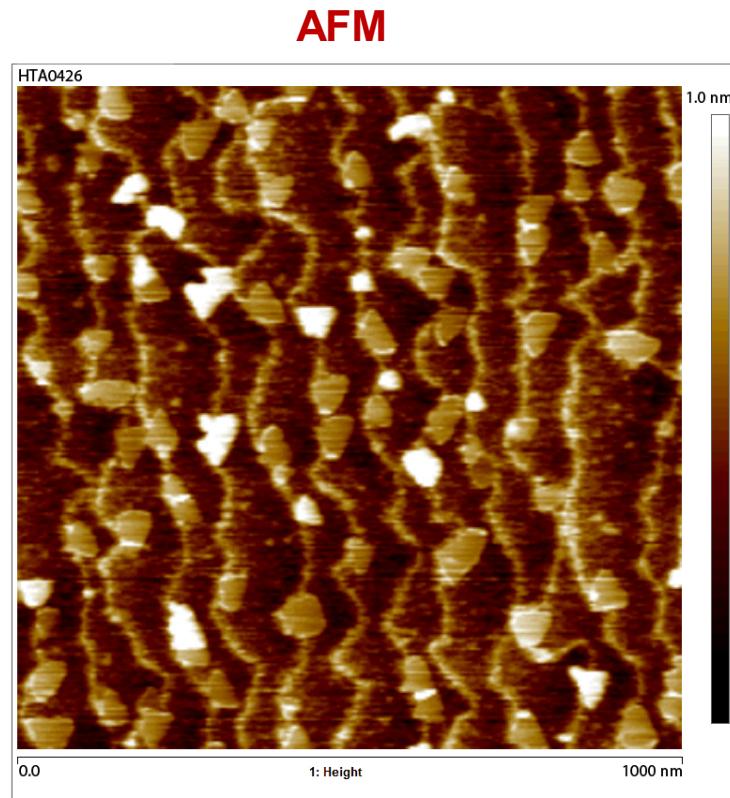
Nucleation Theory

- Control of nucleation is critical for heteroepitaxy
- Classical Nucleation:

$$N = Ce^{-\Delta G/kT}$$

↑ Nuclei Density ↑ Adatom Density ↑ Temperature

- Would expect:
 - Higher temperature = Less nuclei
 - More precursor = More nuclei

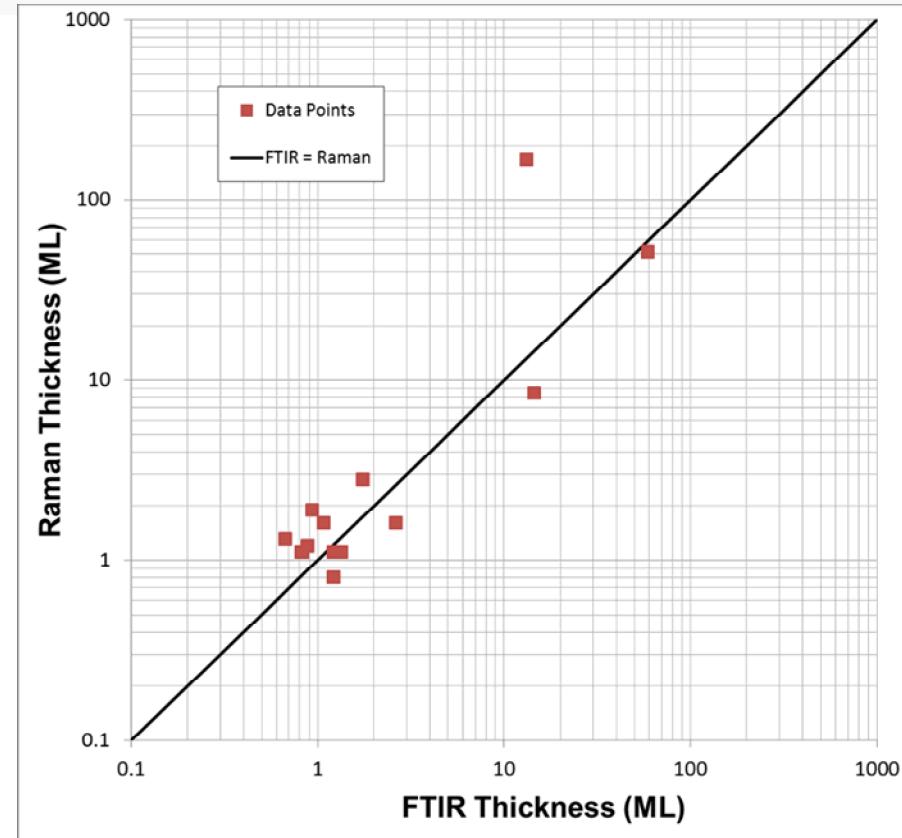


BN nuclei on sapphire
Deposition at 1450 °C

Comparison of Two Techniques

| Sample | FTIR Thickness (ML) | Raman Thickness (ML) |
|--------|------------------------|-------------------------|
| 427 | 0.83 | 1.1 |
| 444 | 0.85 | 0 |
| 445 | 0.89 | 1.2 |
| 468 | 59.39 | 51 |
| 473 | 13.22 | 168* |
| 474 | 14.55 | 8.4 |
| 476 | 1.22 | 1.1 |
| 478 | 2.64 | 1.6 |
| 479 | 0.94 | 1.9 |
| 480 | 0.55 | 0 |
| 481 | 0.82 | 1.1 |
| 482 | 0.67 | 1.3 |
| 485 | 1.34 | 1.1 |
| 488 | 1.22 | 0.8 |
| 489 | 1.76 | 2.8 |
| 490 | 1.08 | 1.6 |

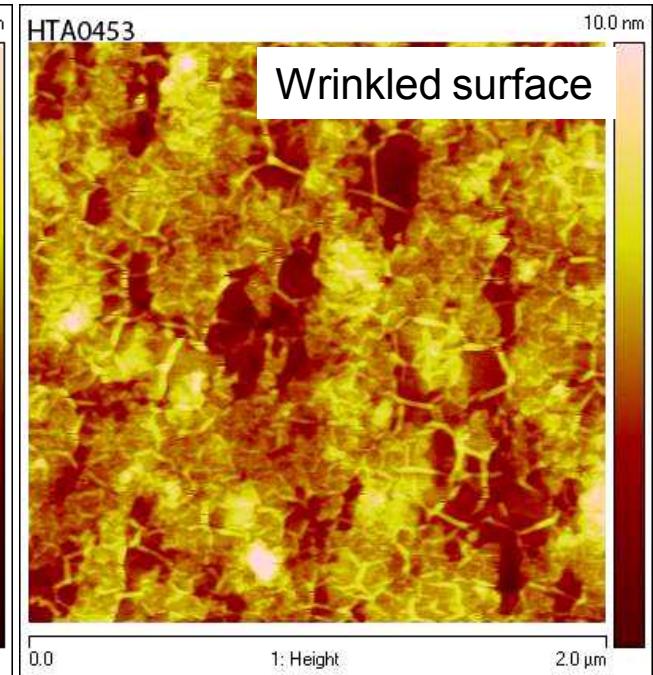
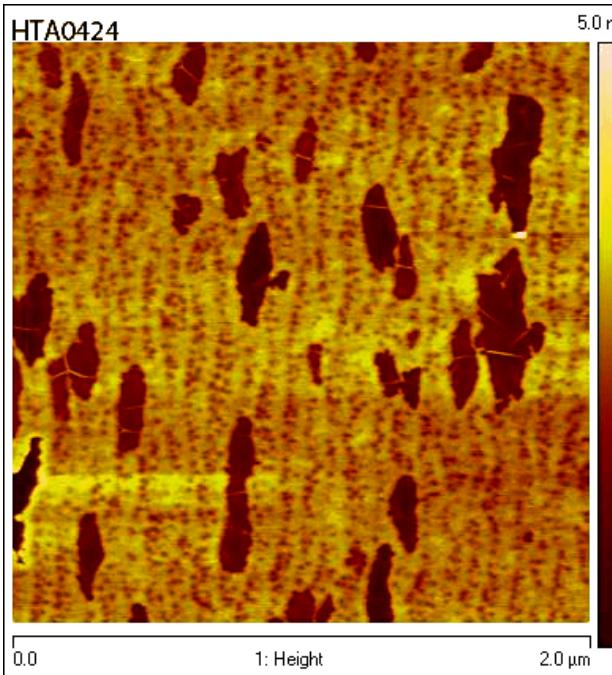
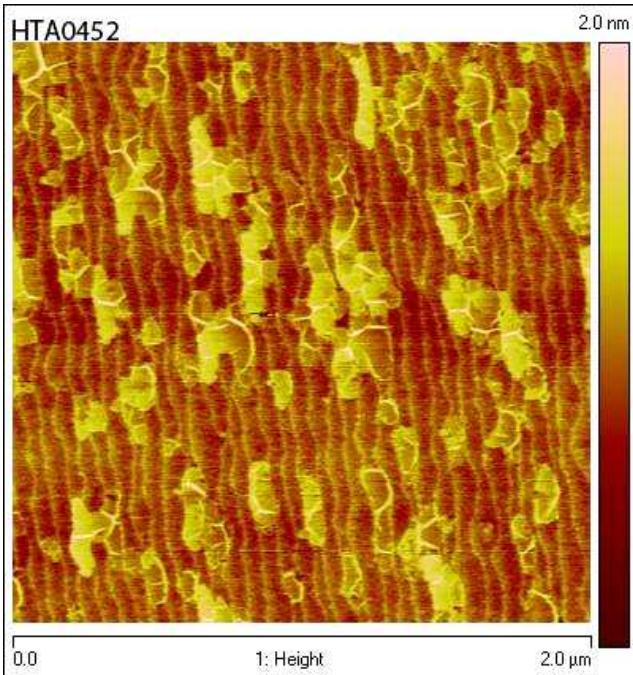
* Anomalous data point



- No systematic over or underestimation between approaches

Morphology

Atomic Force Microscope images: 3 characteristic morphologies



1 monolayer or less

RMS roughness \sim 0.2 nm

1 to 3 monolayers

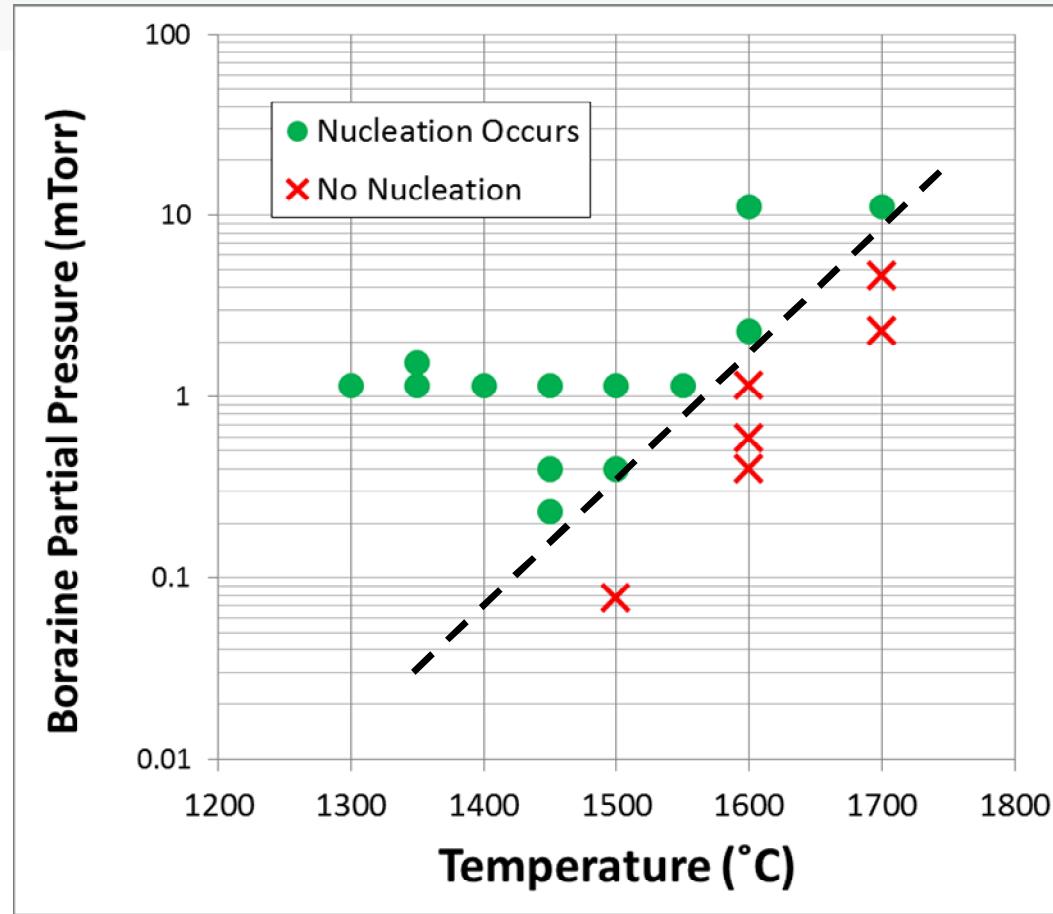
RMS roughness \sim 0.5 nm

3 monolayers or more

RMS roughness $>$ 1 nm

- **Morphology dependent only on film thickness**
- **Growth temperature and borazine flux impact only nucleation**

Experimental Nucleation Studies



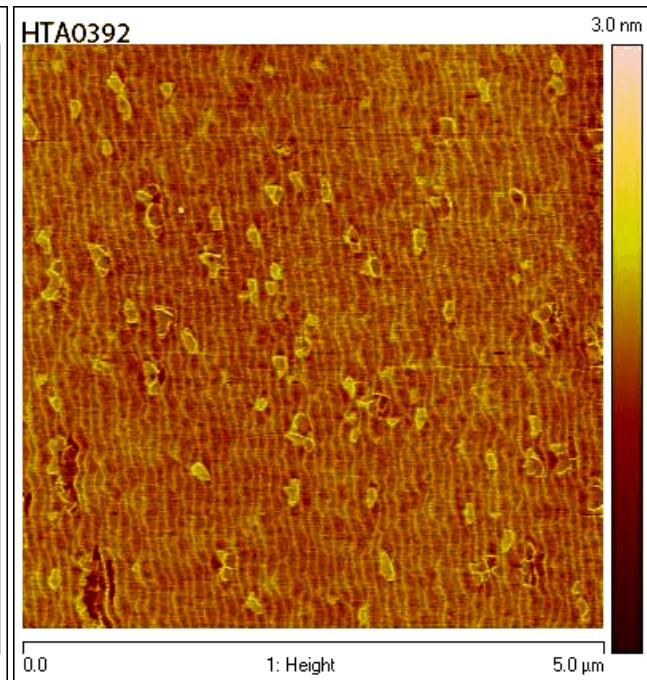
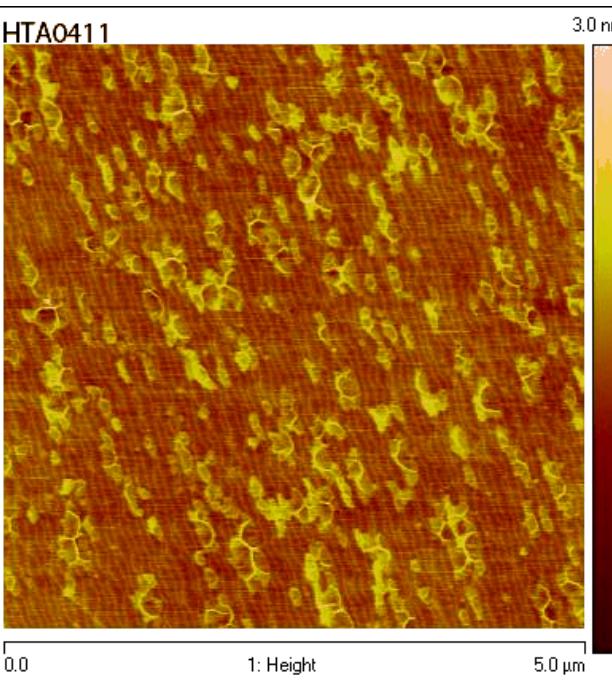
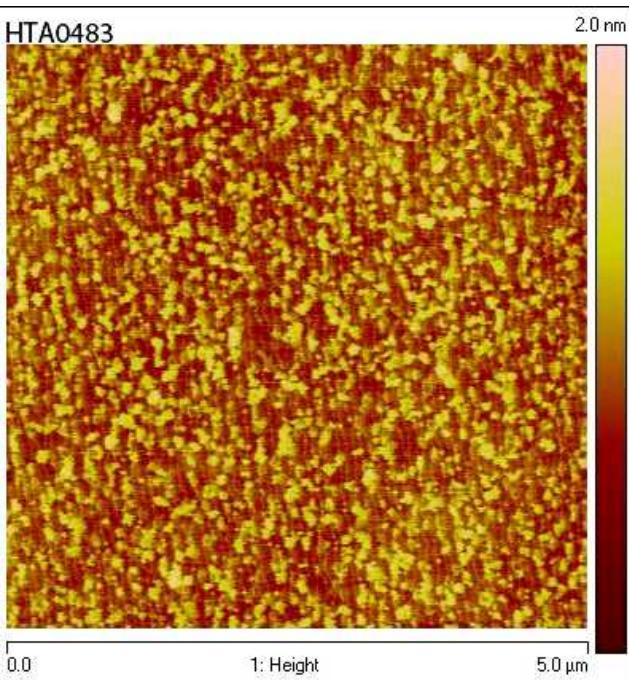
- Critical borazine partial pressure for nucleation to occur
- Strong function of growth temperature

Nucleation with Flux

2 min at 1.5 $\mu\text{mol}/\text{min}$

5 min at 0.75 $\mu\text{mol}/\text{min}$

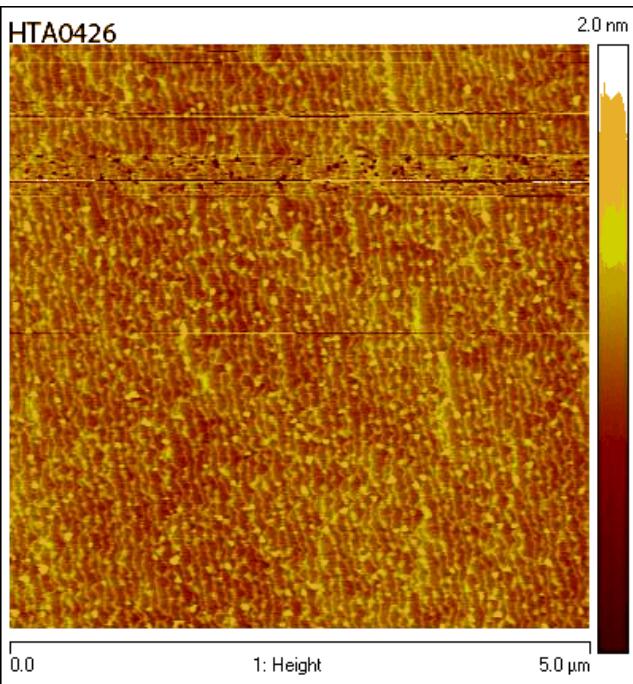
5 min at 0.37 $\mu\text{mol}/\text{min}$ +
15 min at 0.13 $\mu\text{mol}/\text{min}$



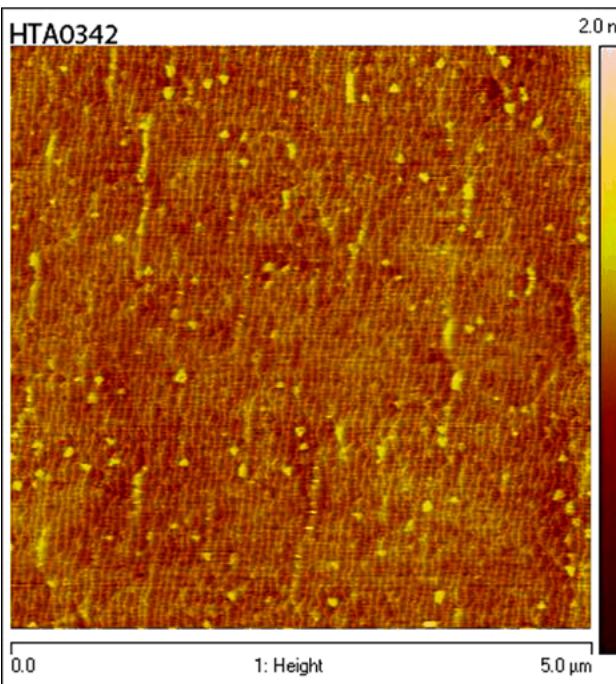
- Fixed temperature of 1600 °C
- Nuclei density decreases with decreasing flux
 - Consistent with classical nucleation theory

Nucleation with Temperature

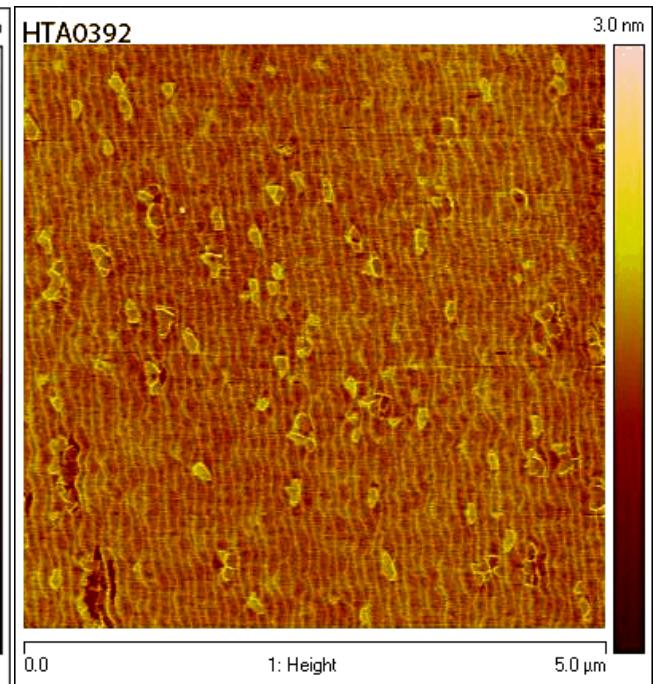
1450 °C



1500 °C



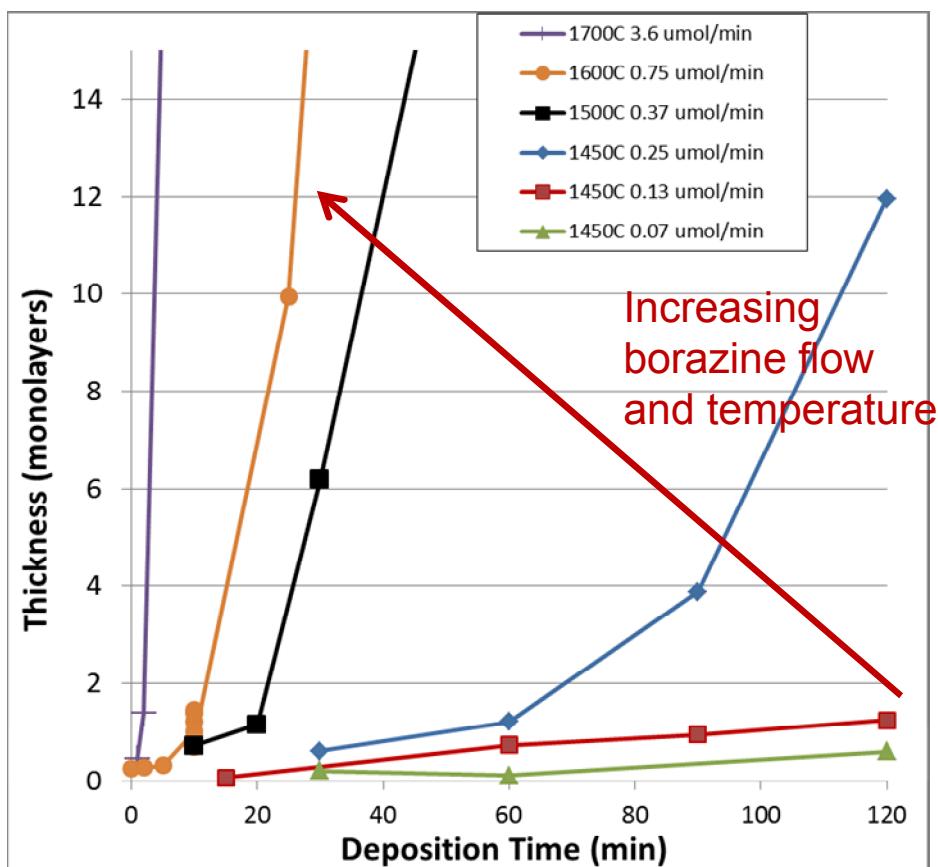
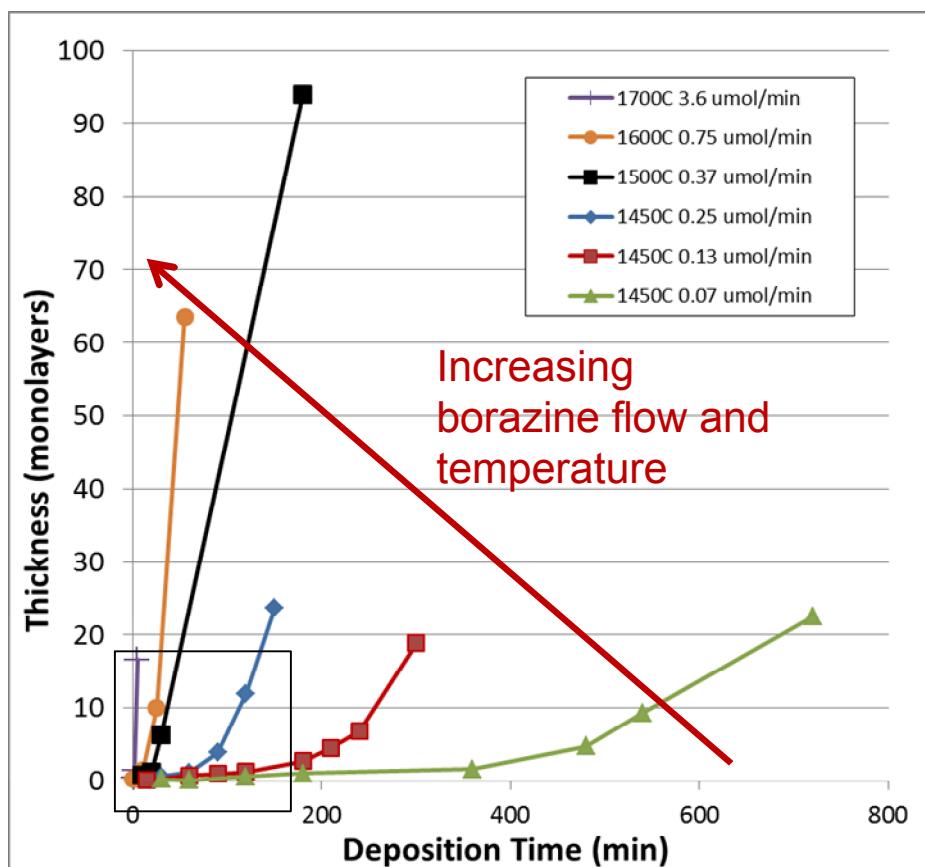
1600 °C



- **Fixed flux and dosage of borazine**
 - 5 min at 0.37 μ mol/min + 15 min at 0.13 μ mol/min
- **Nuclei density decreases with increasing temperature**
 - Consistent with classical nucleation theory

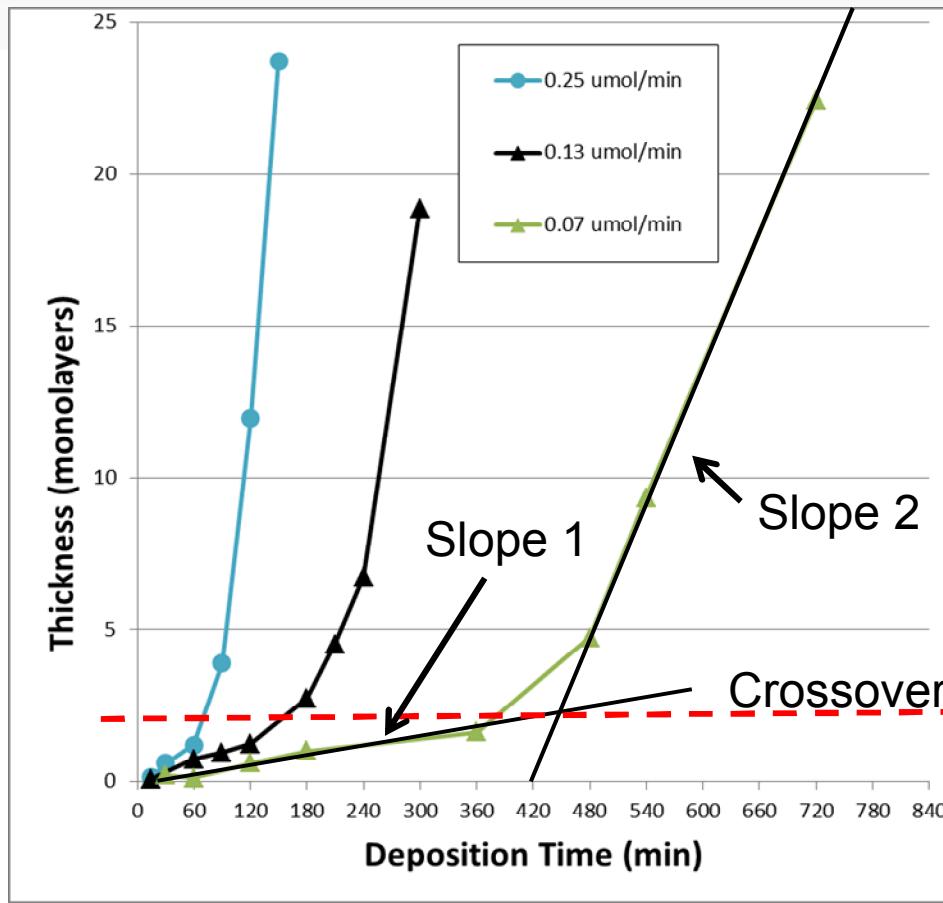
Film Deposition with Borazine

Expanded View



- Deposition rate is not constant with time

Film Deposition with Borazine



- Change in deposition behavior consistently seen at ~2 monolayers

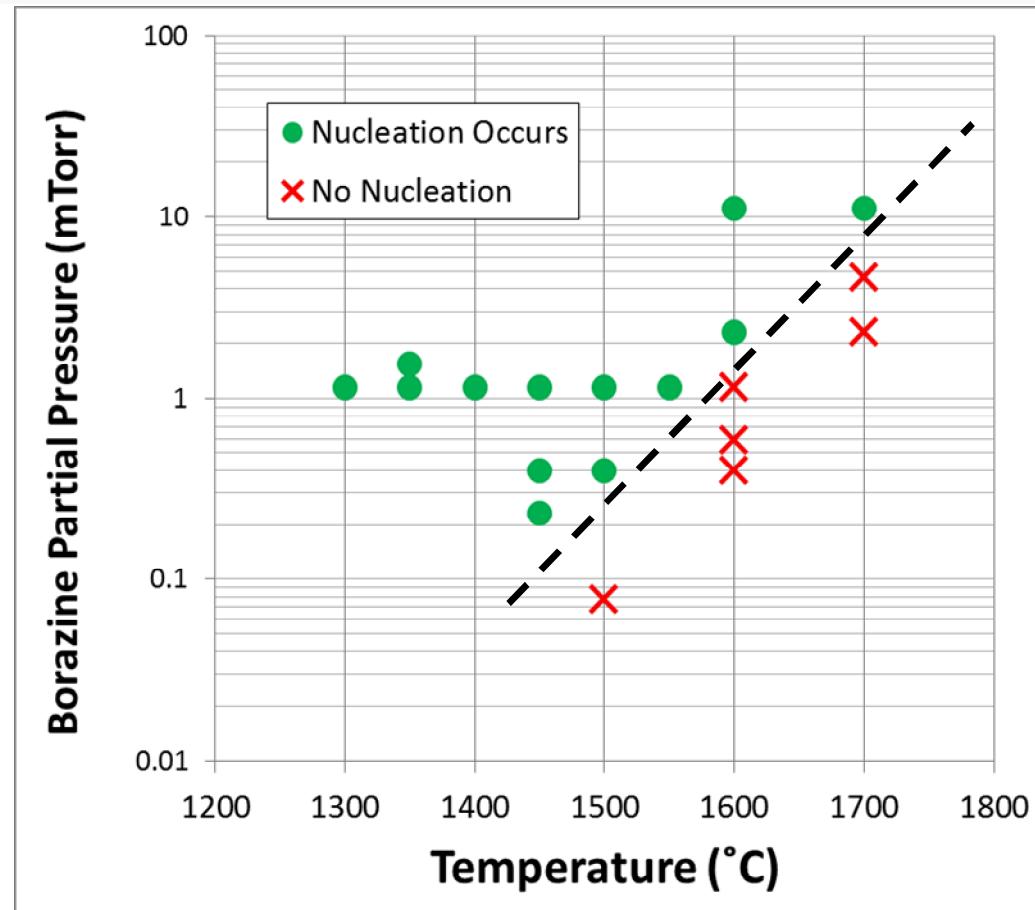
Separating Nucleation and Growth

Nucleation

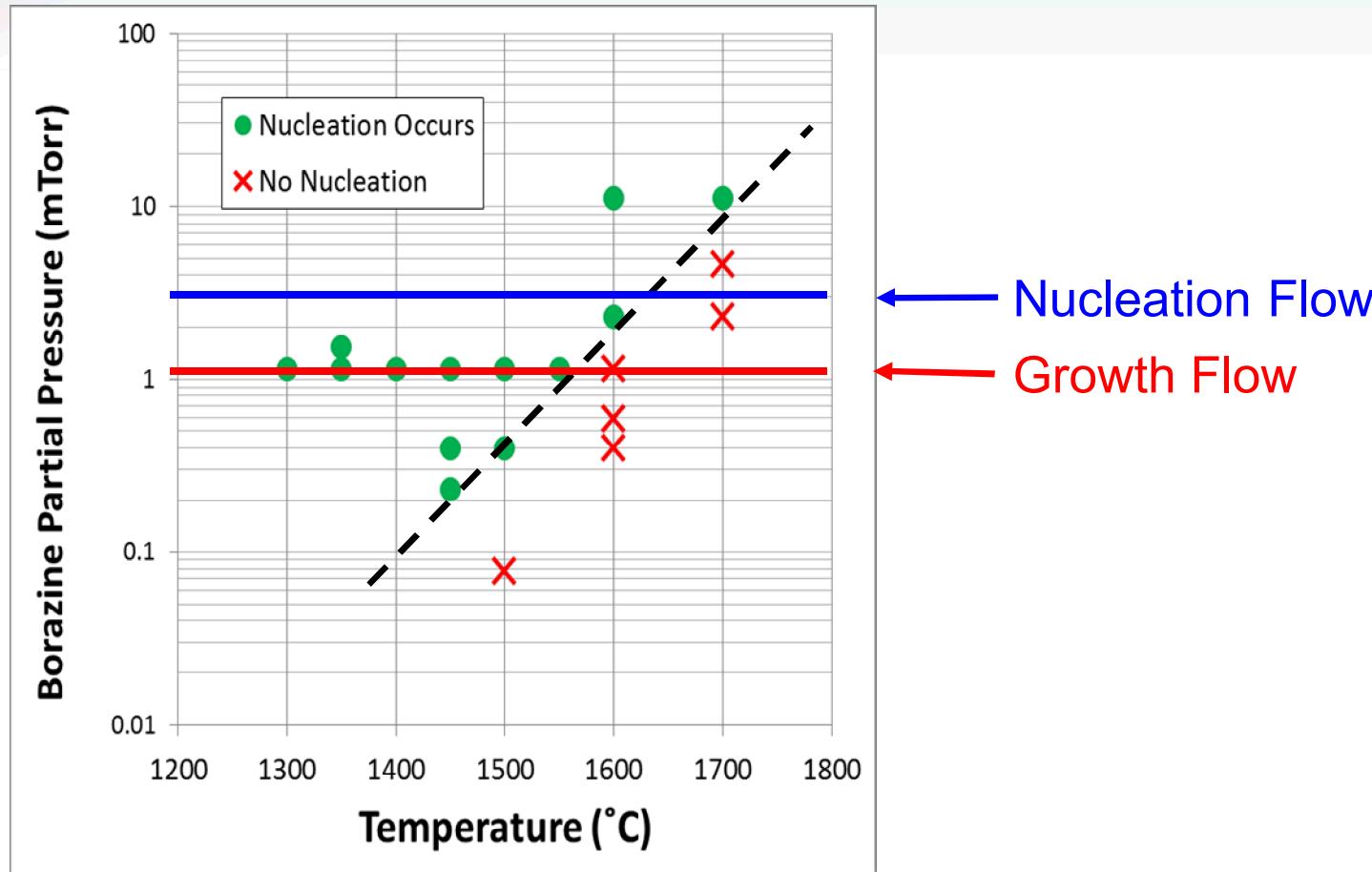
- Threshold determined by supersaturation
- Must over come an energetic barrier to nucleate

Deposition

- Net mass flux to growth surface must be positive
- Just need a higher input partial pressure than equilibrium partial pressure



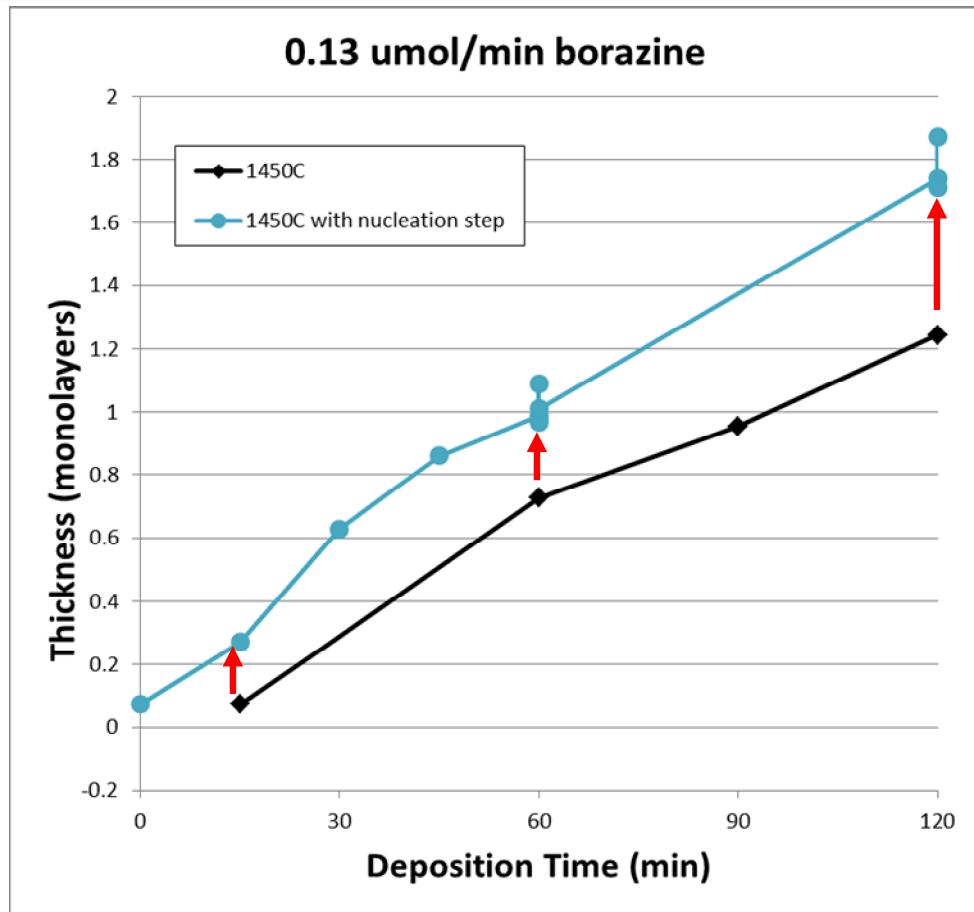
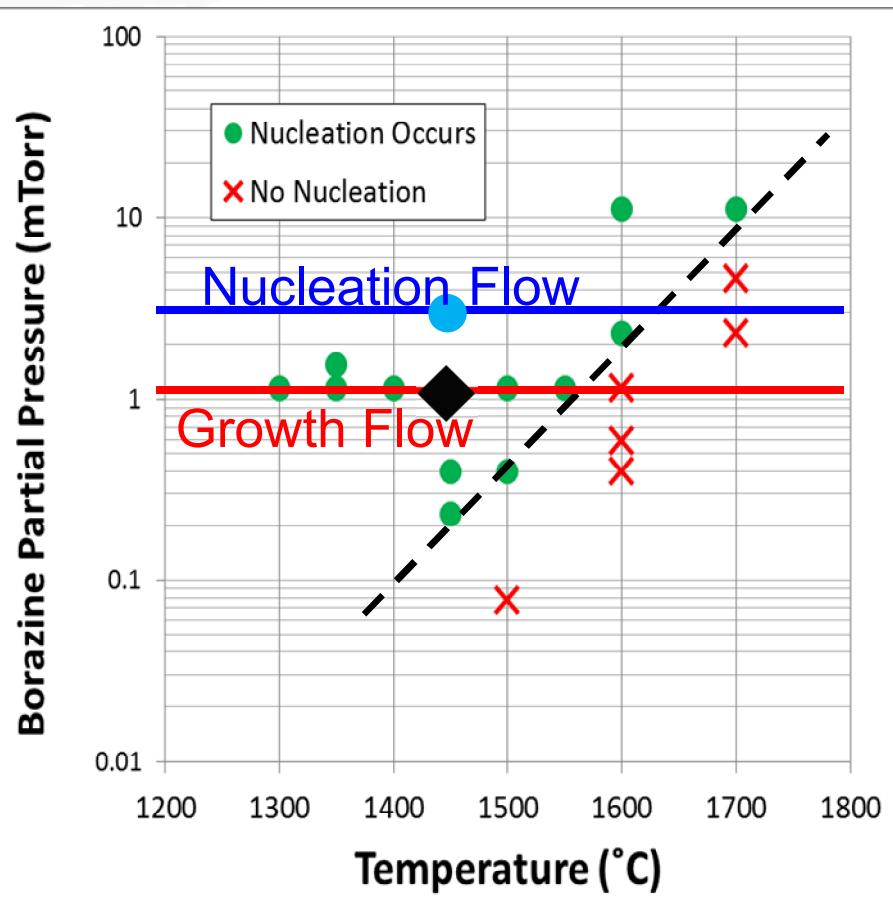
Separating Nucleation and Growth



- “Nucleation step” is 5 minutes at 0.37 $\mu\text{mol}/\text{min}$ borazine
- Growth at 0.13 $\mu\text{mol}/\text{min}$ borazine

Separating Nucleation and Growth

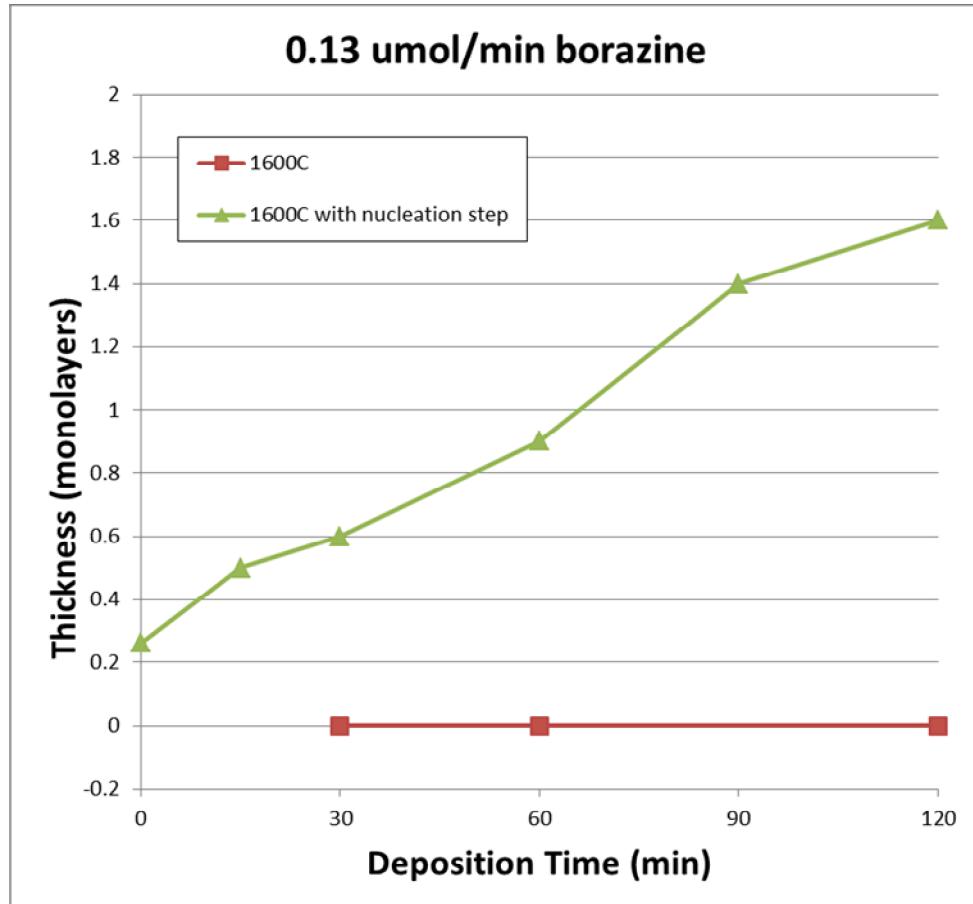
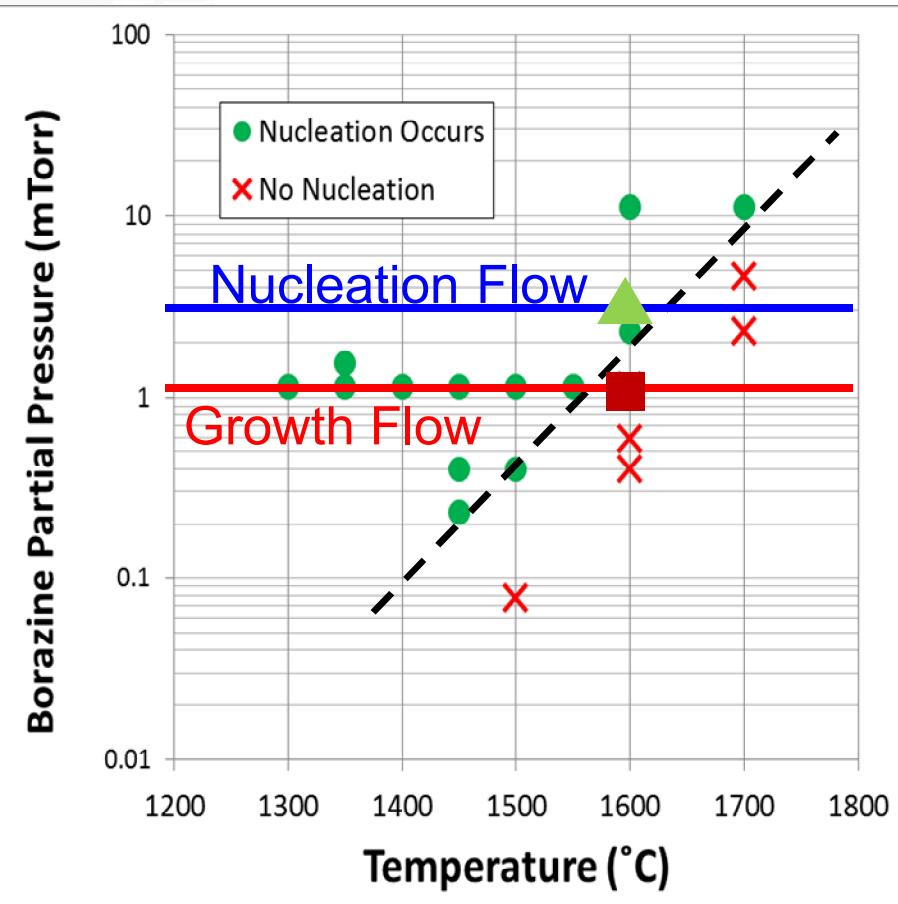
Case 1: $T_g = 1450C$



- “Nucleation step” is 5 minutes at $0.37 \mu\text{mol}/\text{min}$ borazine
- Growth at $0.13 \mu\text{mol}/\text{min}$ borazine

Separating Nucleation and Growth

Case 2: $T_g = 1600C$



- “Nucleation step” is 5 minutes at 0.37 $\mu\text{mol}/\text{min}$ borazine
- Growth at 0.13 $\mu\text{mol}/\text{min}$ borazine

→ Nucleation step is critical for higher growth temperatures